

DDR II

Outline

- DDRI vs. DDRII
- Functional Block Diagram
- Simplified State Diagram
- Action of Functional signal Description

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Different points

DDR v.s. DDR2

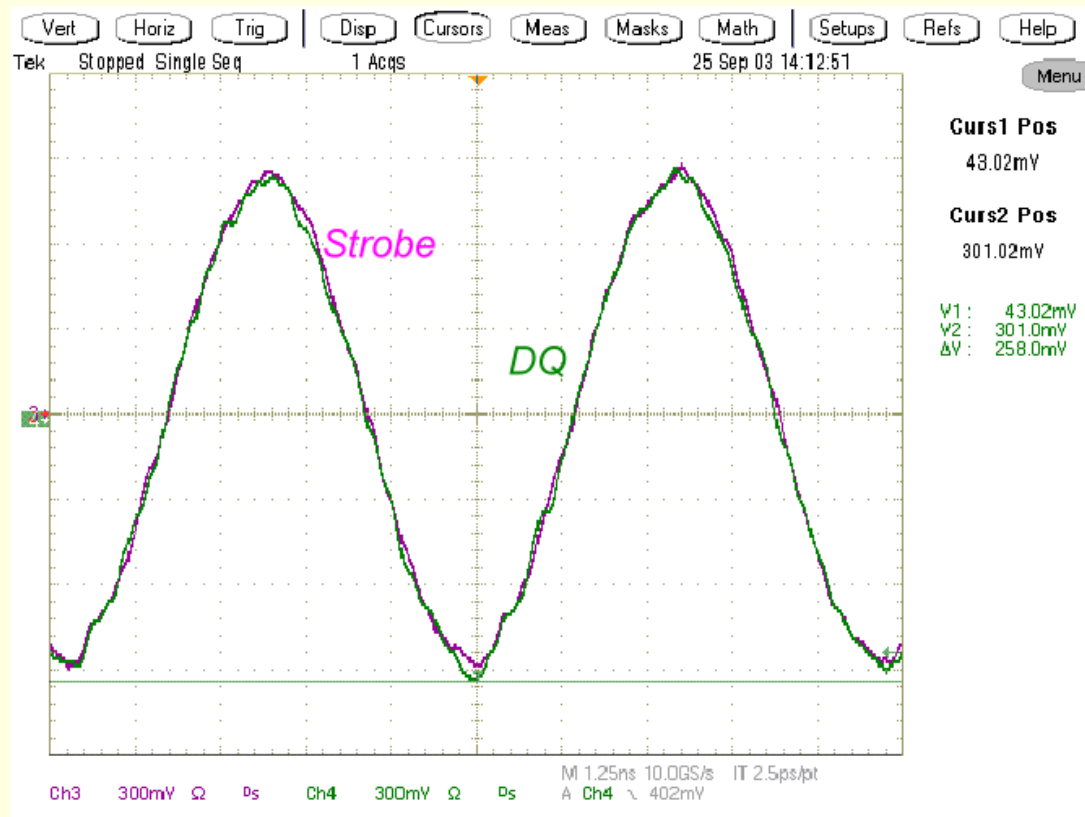
| Memory Type | DDR | DDR2 |
|--------------------|---|--|
| Core Voltage(VDD) | 2.5V | 1.8V |
| I/O Voltage (VDDQ) | SSTL_2(2.5V) | SSTL_1.8(1.8) |
| Data Rate | 200/266/333/400Mbps | 400/533/667/800Mbps |
| Bus Frequency | 100/133/166/200MHz | 200/266/333/400MHz |
| Core Frequency | 100/133/166/200MHz | 100/133/166/200MHz |
| Pre-fetch | 2-bit | 4-bit |
| Burst Length | 2/4/8 | 4/8 |
| Data Strobe | Single DQS | Differential DQS, /DQS |
| Write Latency | 1 clock | (Read Latency -1) clock |
| CAS Latency | 1.5, 2, 2.5 | 3, 4, 5 |
| Package | x4/x8/x16: 66-pin TSOP(II) x4/x8/x16: 60-ball FBGA | x4/x8: 60 ball FBGA x16: 84 ball FBGA |
| New Features | | OCD ODT Posted CAS |

Power Improvement

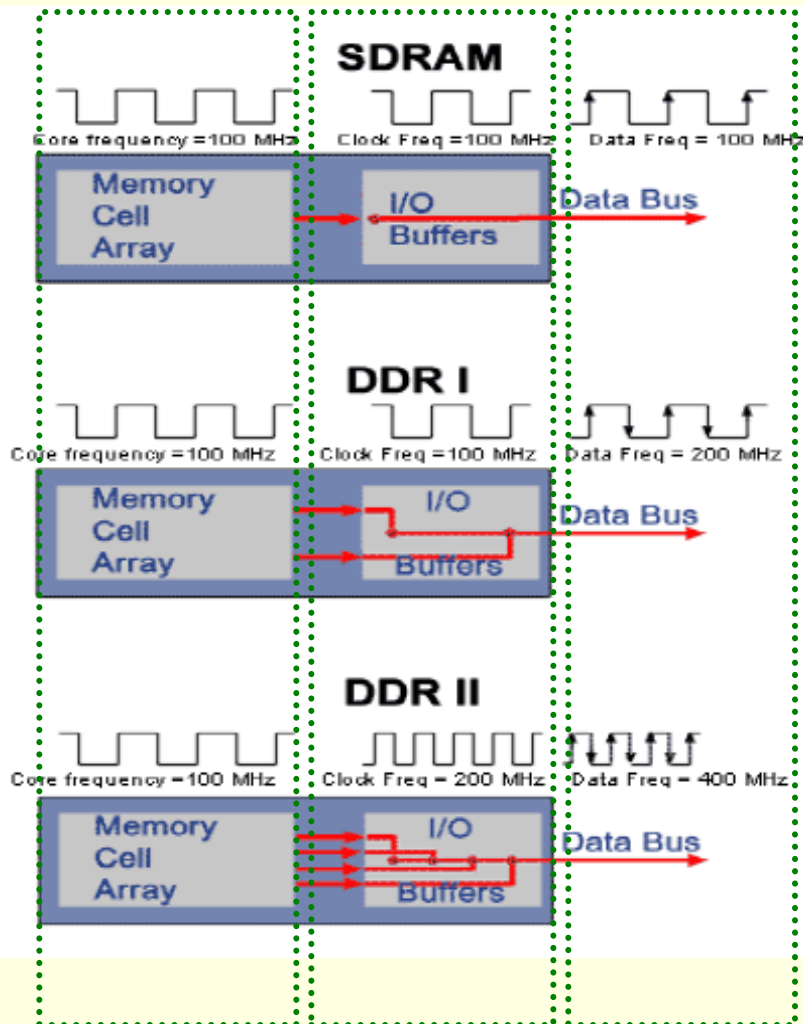
- Reduced operating voltage allows power saving
- Reduced voltage swing allows higher frequency
- Support for disabling DLL during Power Down Mode
- Less power to activate sense amps

DLL (Delay Lock Loop)

- DLL aligns DQ and DQS transitions with CK transitions

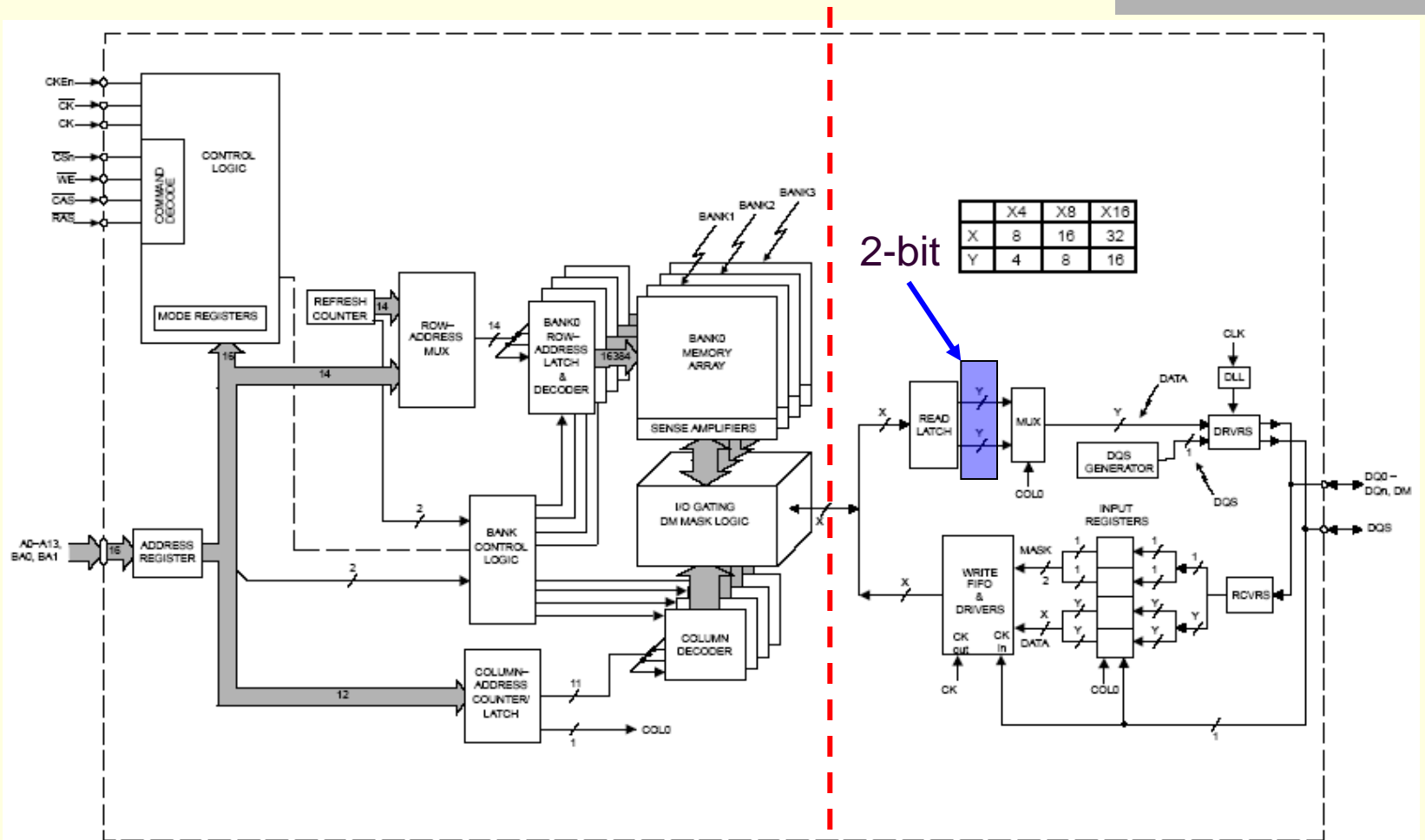


SDR, DDR and DDR2 clock comparison

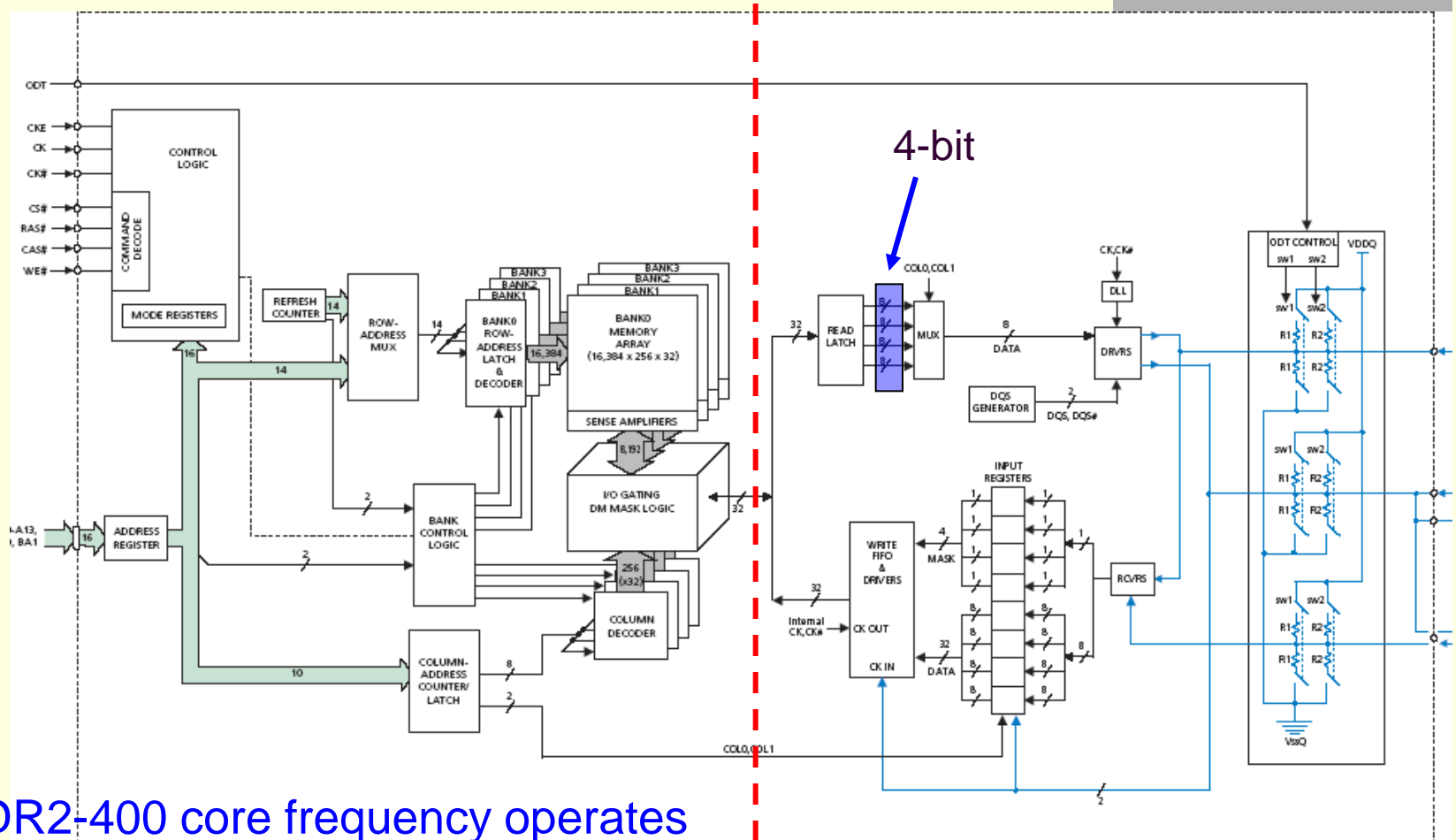


| Item | DDR2 SDRAM | DDR SDRAM | SDR SDRAM |
|----------------------------------|------------|-----------|-----------|
| Prefetch | 4 bit | 2 bit | 1 bit |
| Internal bus operating frequency | 100MHz | 100MHz | 100MHz |
| External clock frequency | 200MHz | 100MHz | 100MHz |
| Data bus speed | 400Mbps | 200Mbps | 100Mbps |

DDR1 2-bit Pre-fetch



DDR2 4-bit Pre-fetch



DDR2-400 core frequency operates
at the same speed as DDR200

Burst Length

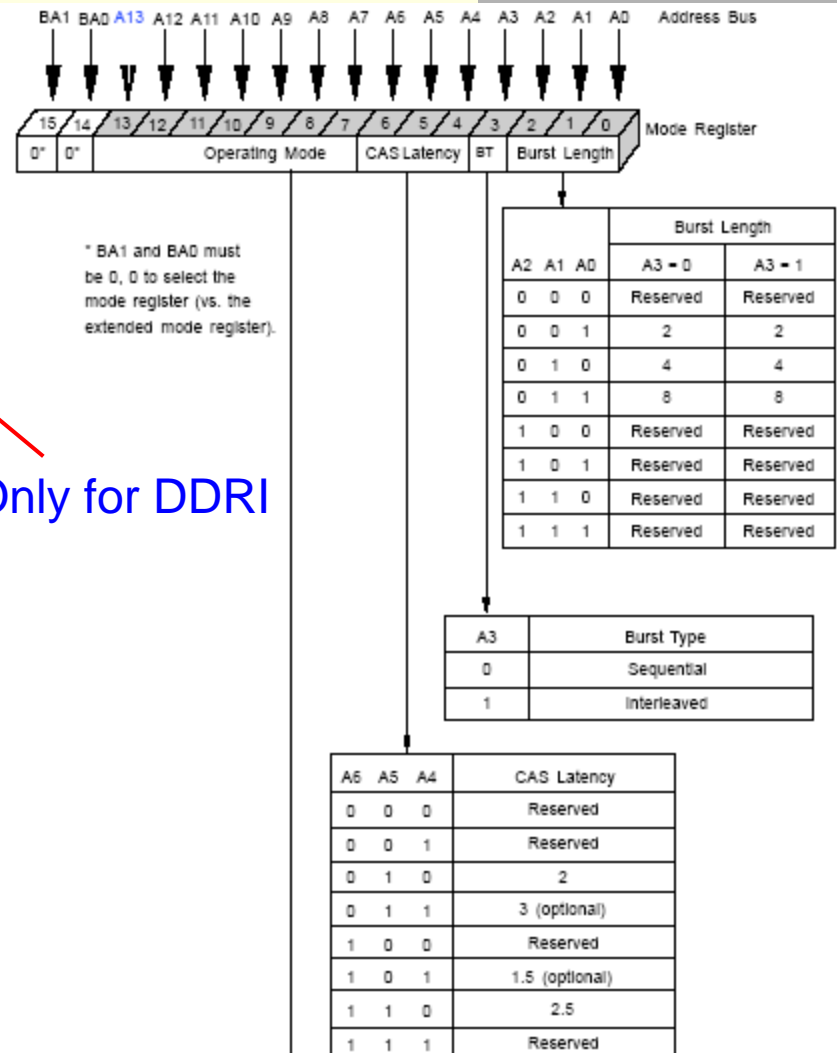
- Burst length determines the maximum number of column locations that can be accessed for a given READ or WRITE command.

Burst Length

BURST DEFINITION

| Burst Length | Starting Column Address | Order of Accesses Within a Burst | |
|--------------|-------------------------|----------------------------------|--------------------|
| | | Type = Sequential | Type = Interleaved |
| 2 | A0 | | |
| | 0 | 0-1 | 0-1 |
| | 1 | 1-0 | 1-0 |
| 4 | A1 A0 | | |
| | 0 0 | 0-1-2-3 | 0-1-2-3 |
| | 0 1 | 1-2-3-0 | 1-0-3-2 |
| | 1 0 | 2-3-0-1 | 2-3-0-1 |
| | 1 1 | 3-0-1-2 | 3-2-1-0 |
| 8 | A2 A1 A0 | | |
| | 0 0 0 | 0-1-2-3-4-5-6-7 | 0-1-2-3-4-5-6-7 |
| | 0 0 1 | 1-2-3-4-5-6-7-0 | 1-0-3-2-5-4-7-6 |
| | 0 1 0 | 2-3-4-5-6-7-0-1 | 2-3-0-1-6-7-4-5 |
| | 0 1 1 | 3-4-5-6-7-0-1-2 | 3-2-1-0-7-6-5-4 |
| | 1 0 0 | 4-5-6-7-0-1-2-3 | 4-5-6-7-0-1-2-3 |
| | 1 0 1 | 5-6-7-0-1-2-3-4 | 5-4-7-6-1-0-3-2 |
| | 1 1 0 | 6-7-0-1-2-3-4-5 | 6-7-4-5-2-3-0-1 |
| | 1 1 1 | 7-0-1-2-3-4-5-6 | 7-6-5-4-3-2-1-0 |

Only for DDRI



DDR2 Features

- Power Improvement
 - Reduced operating voltage allows power saving
 - Reduced voltage swing allows higher frequency
- Signal Integrity Improvement
 - Off Chip Driver (OCD) Calibration
 - On Die Termination (ODT)
- Posted CAS Mode
- 4bit Pre-fetch Architecture
 - Transfer four data word per clock cycle at the I/O pins
 - Core frequency run at the same speed as DDR

OCD (Off-Chip Driver) Calibration

- The I/O driver resistance is set to adjust the voltage to equalize the pull-up/pull-down resistance.

OCD (Off-Chip Driver) Calibration

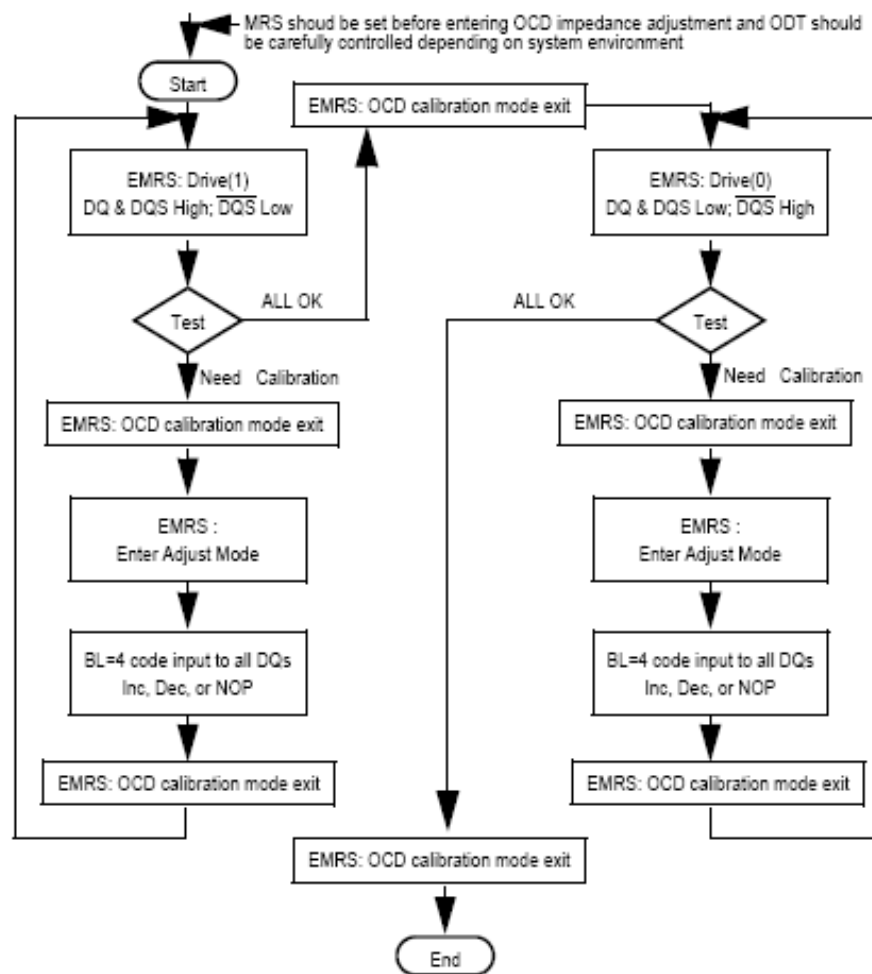
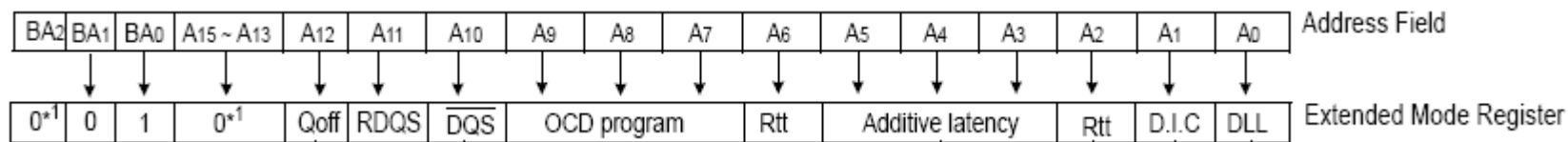


Figure 12 — OCD impedance adjustment

OCD (Off-Chip Driver) Calibration



↓

| A9 | A8 | A7 | Operation |
|----|----|----|---|
| 0 | 0 | 0 | OCD calibration mode exit |
| 0 | 0 | 1 | Drive(1) DQ, DQS, (RDQS) high and $\overline{\text{DQS}}$ low |
| 0 | 1 | 0 | Drive(0) DQ, DQS, (RDQS) low and $\overline{\text{DQS}}$ high |
| 1 | 0 | 0 | Adjust mode |
| 1 | 1 | 1 | OCD calibration default |

OCD (Off-Chip Driver) Calibration

- Drive Mode is used for controllers to measure DDR2 SDRAM Driver impedance.

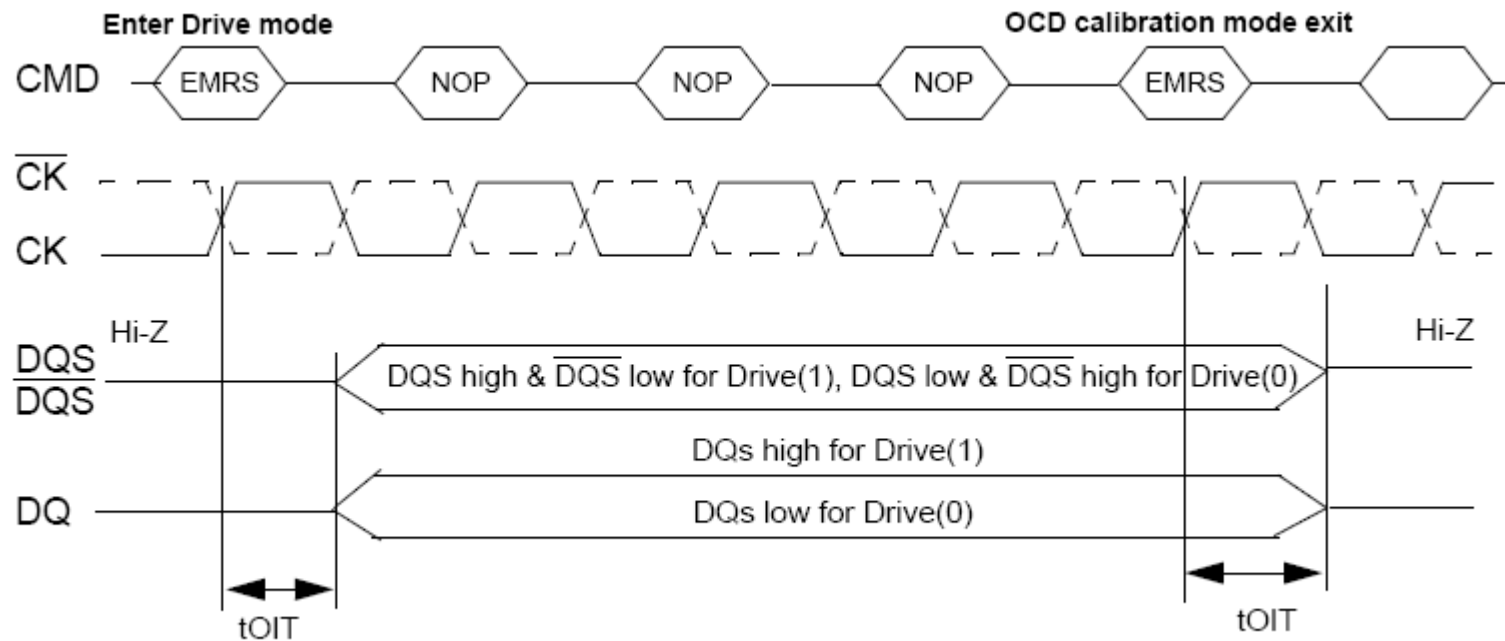
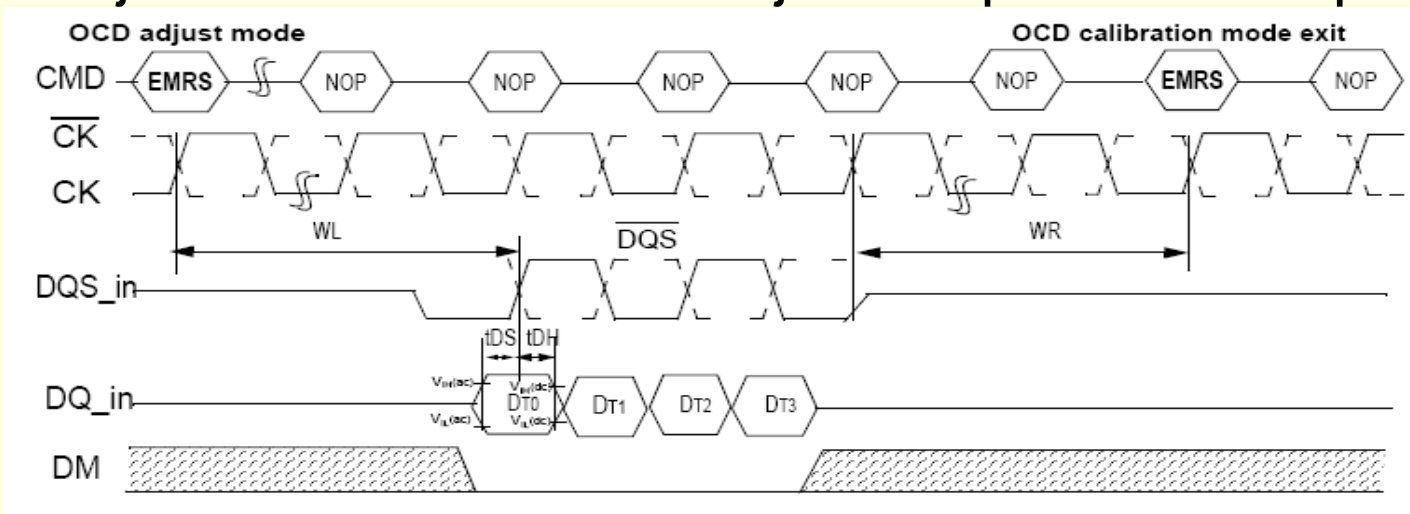


Figure 14 — OCD drive mode

OCD (Off-Chip Driver) Calibration

- Adjust Mode is used to adjust output driver impedance.



| 4bit burst code inputs to all DQs | | | | Operation | |
|-----------------------------------|-----|-----|-----|-------------------------|---------------------------|
| DT0 | DT1 | DT2 | DT3 | Pull-up driver strength | Pull-down driver strength |
| 0 | 0 | 0 | 0 | NOP (No operation) | NOP (No operation) |
| 0 | 0 | 0 | 1 | Increase by 1 step | NOP |
| 0 | 0 | 1 | 0 | Decrease by 1 step | NOP |
| 0 | 1 | 0 | 0 | NOP | Increase by 1 step |
| 1 | 0 | 0 | 0 | NOP | Decrease by 1 step |
| 0 | 1 | 0 | 1 | Increase by 1 step | Increase by 1 step |
| 0 | 1 | 1 | 0 | Decrease by 1 step | Increase by 1 step |
| 1 | 0 | 0 | 1 | Increase by 1 step | Decrease by 1 step |
| 1 | 0 | 1 | 0 | Decrease by 1 step | Decrease by 1 step |
| Other Combinations | | | | Reserved | |

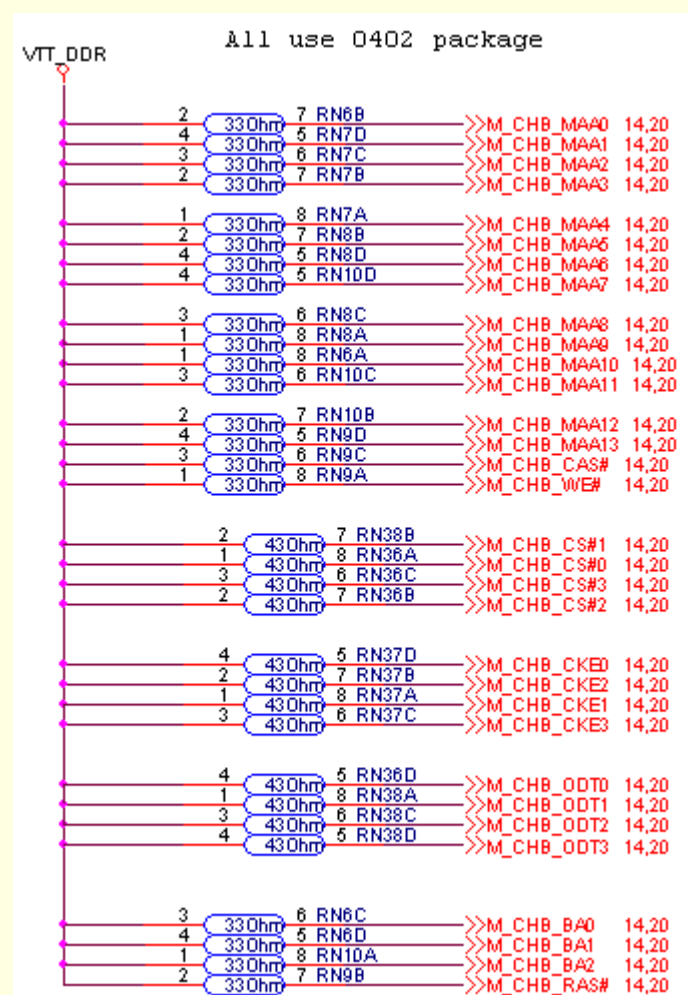
On Die Termination (ODT)

- Improved signal integrity
 - Control reflected noise on the transfer line
- Reduction of parts cost
 - Reduce the parts counts on the mother board
- Easier system design
 - Eliminate the complicated placement and routing for termination

On Die Termination (ODT)

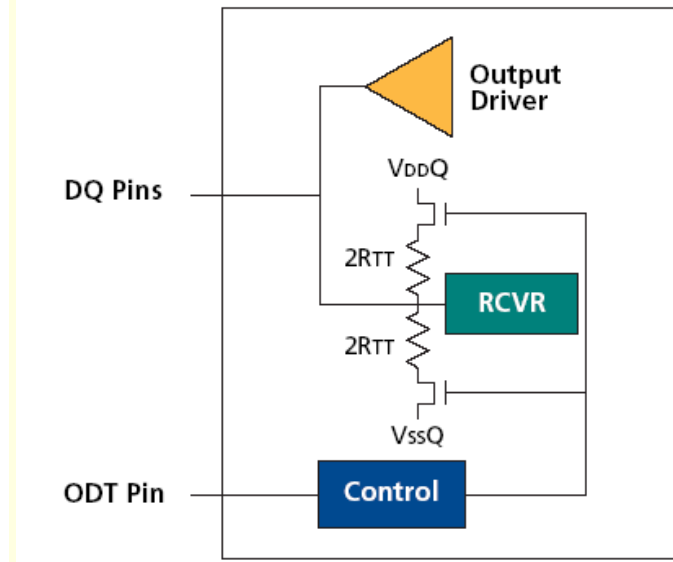
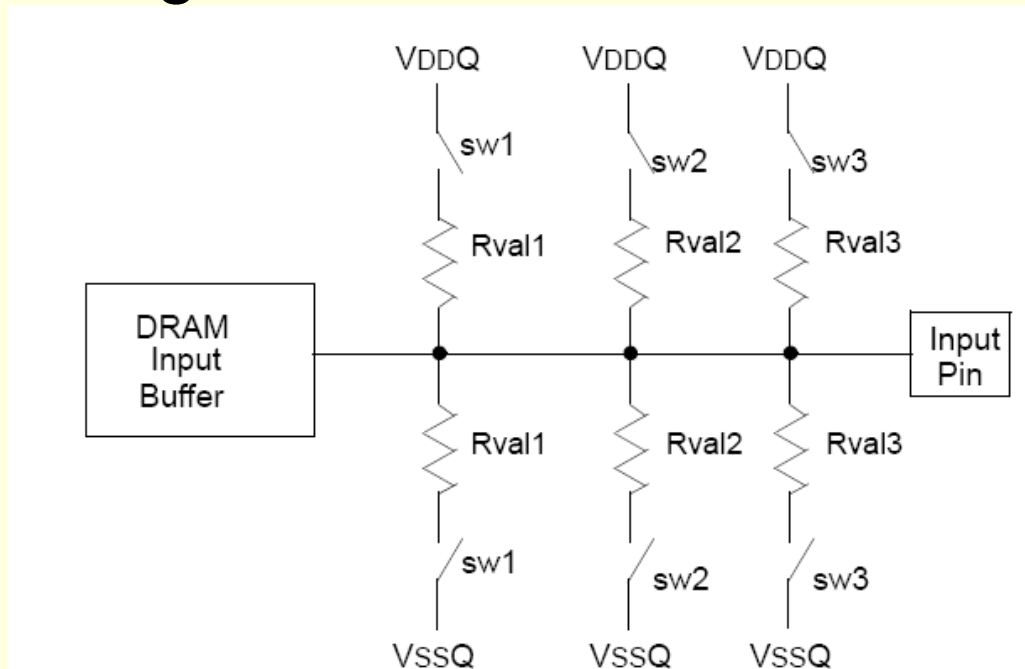
DDRI DQ,DM,DQS,DQS#

DDRII



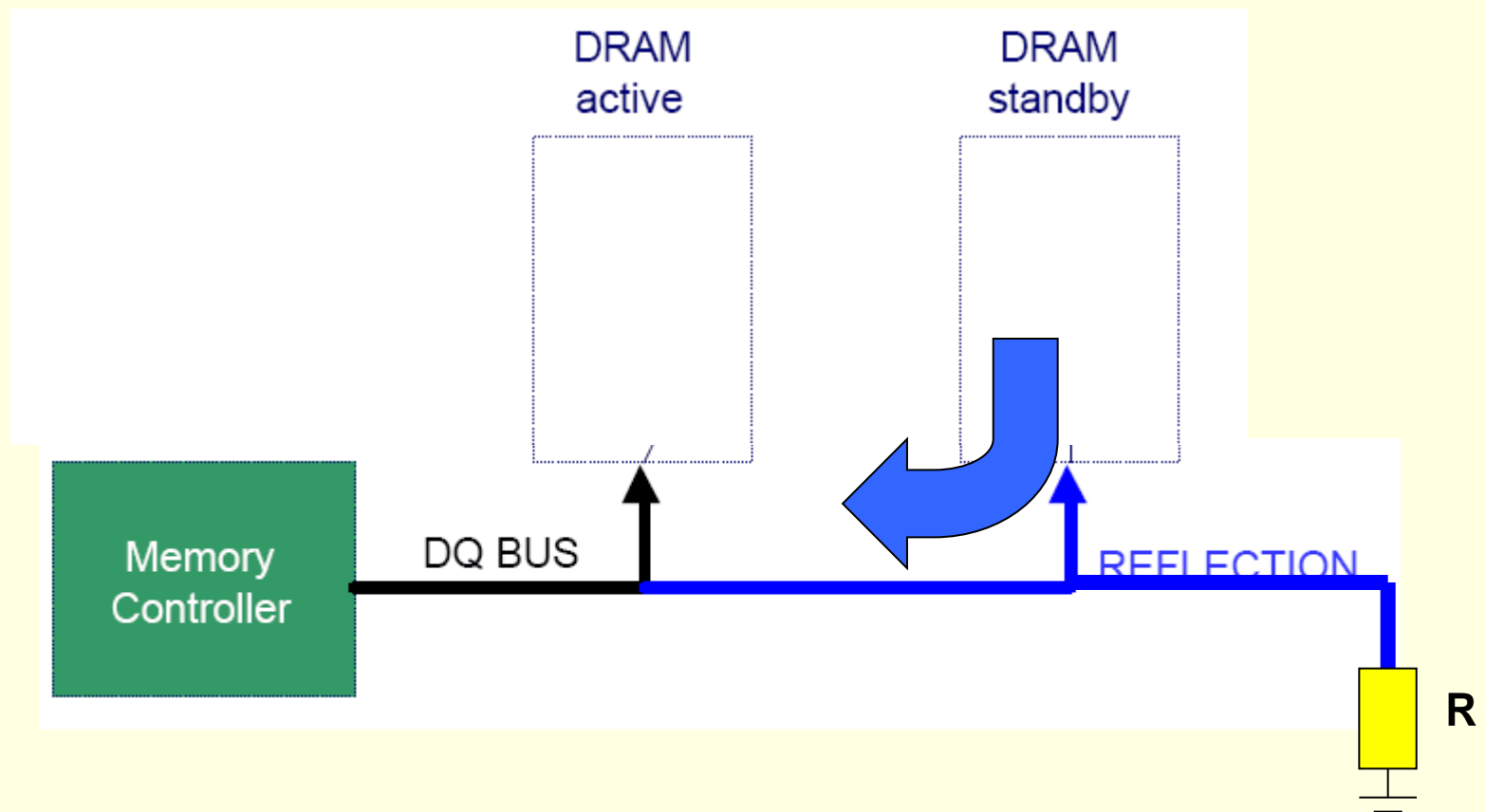
On Die Termination (ODT)

- On Die Termination (ODT) allows a DRAM to turn on/off termination resistance for each DQ, DQS/DQS#, RDQS/RDQS#, and DM signal.



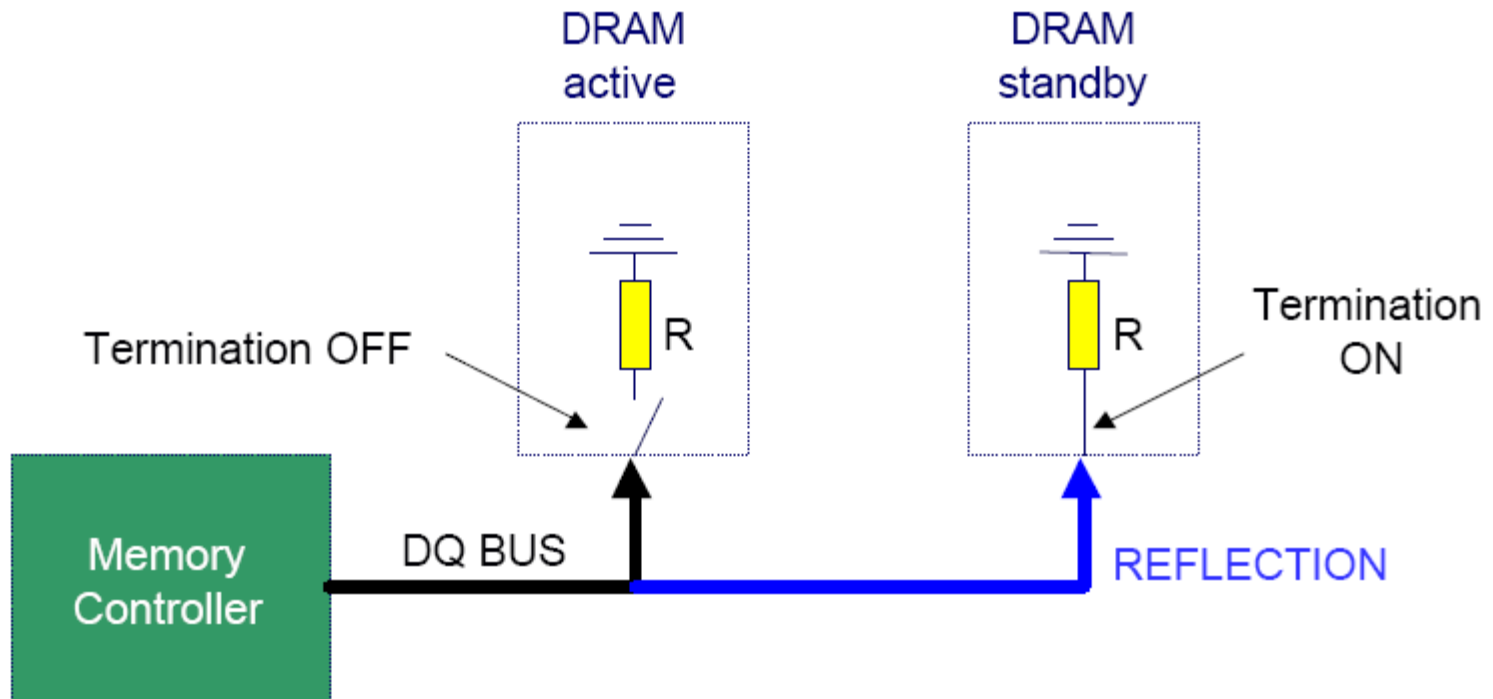
On Die Termination (ODT)

■ DDRI

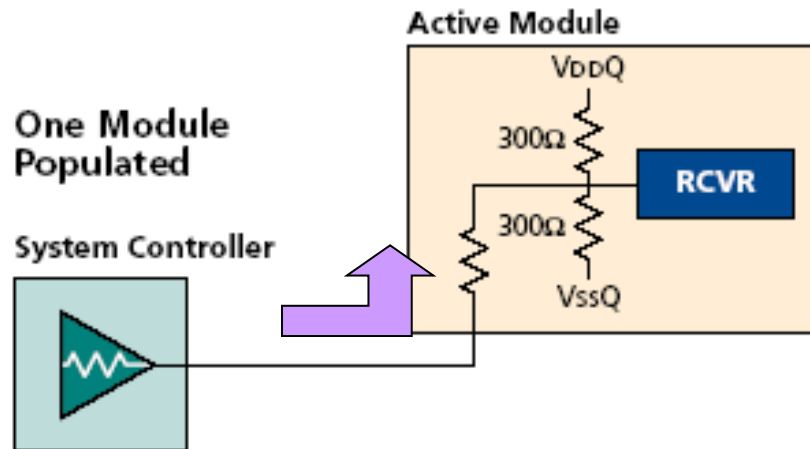


On Die Termination (ODT)

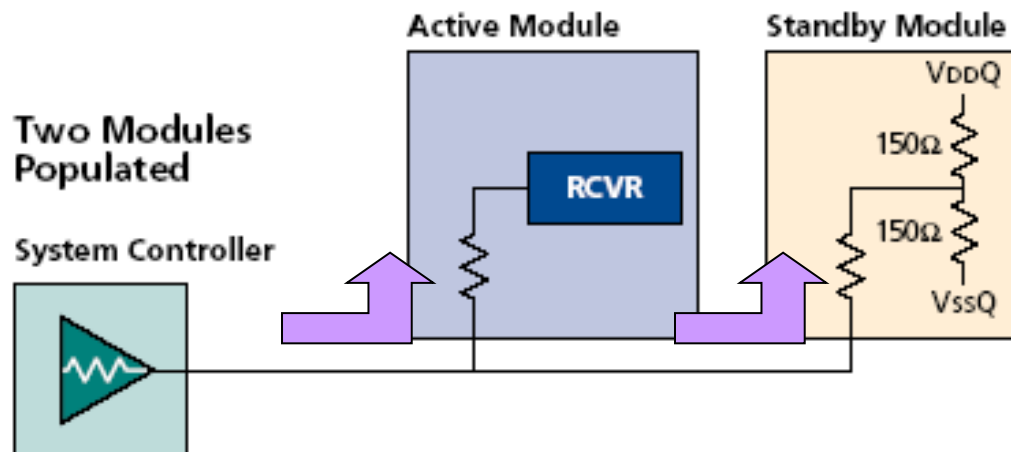
■ DDRII



ODT WRITE

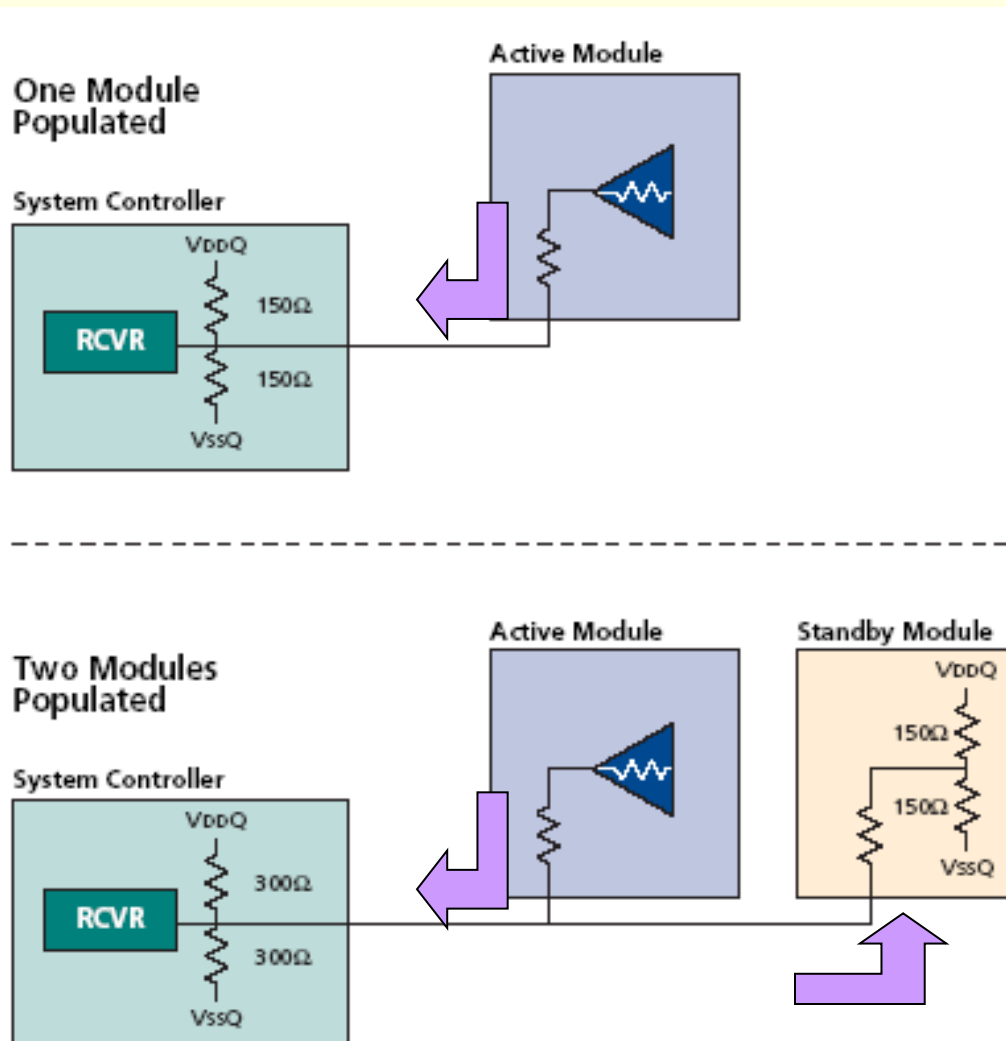


$$300//300\text{ohm}=150\text{ohm}$$

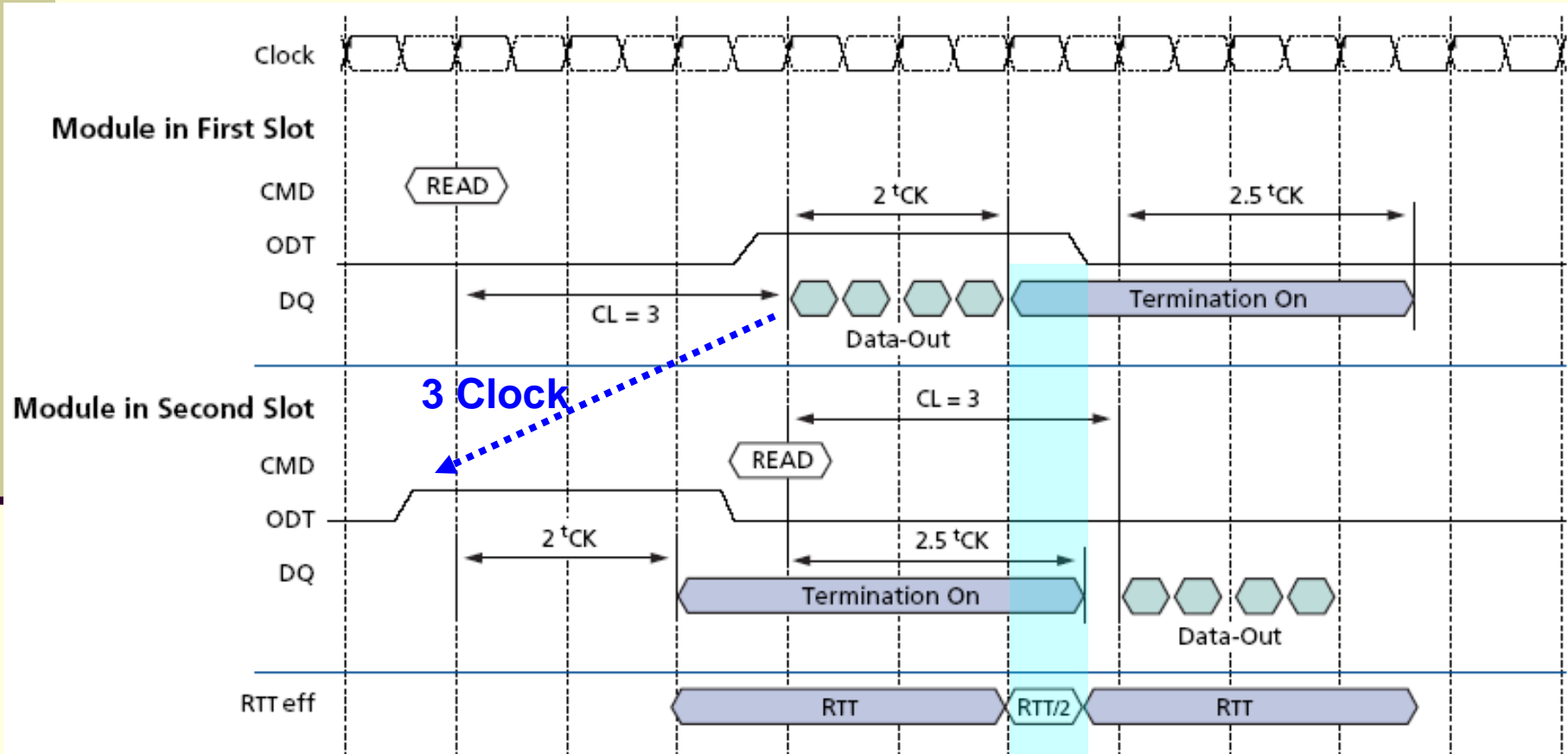


$$150//150\text{ohm}=75\text{ohm}$$

ODT READ

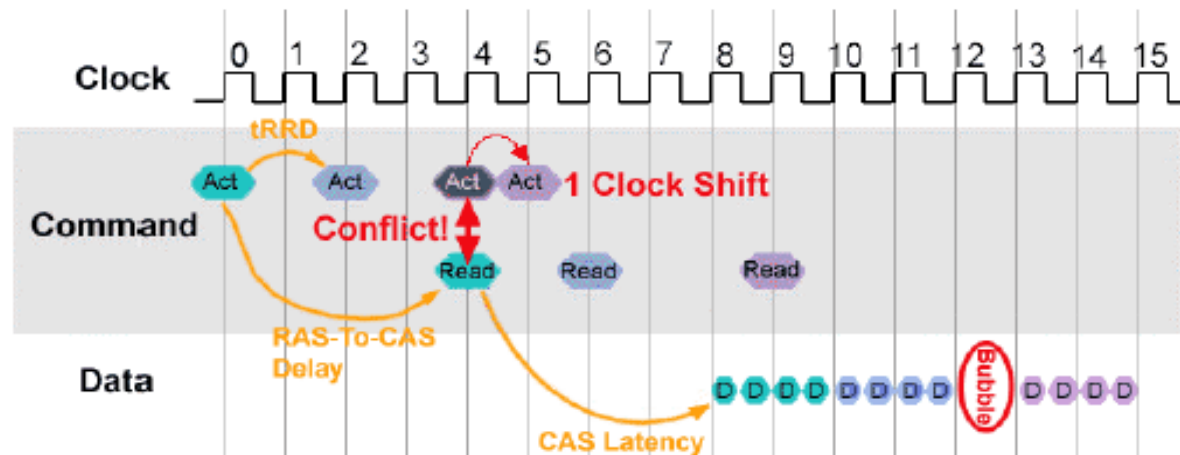


Rank-to-Rank ODT Control – READs

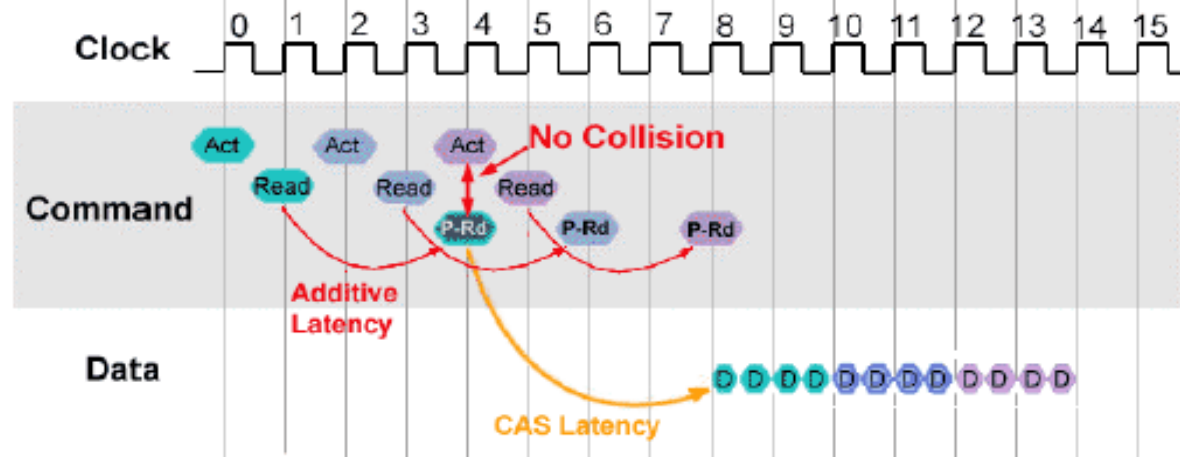


Posted CAS Mode

Conventional command



Posted CAS mode



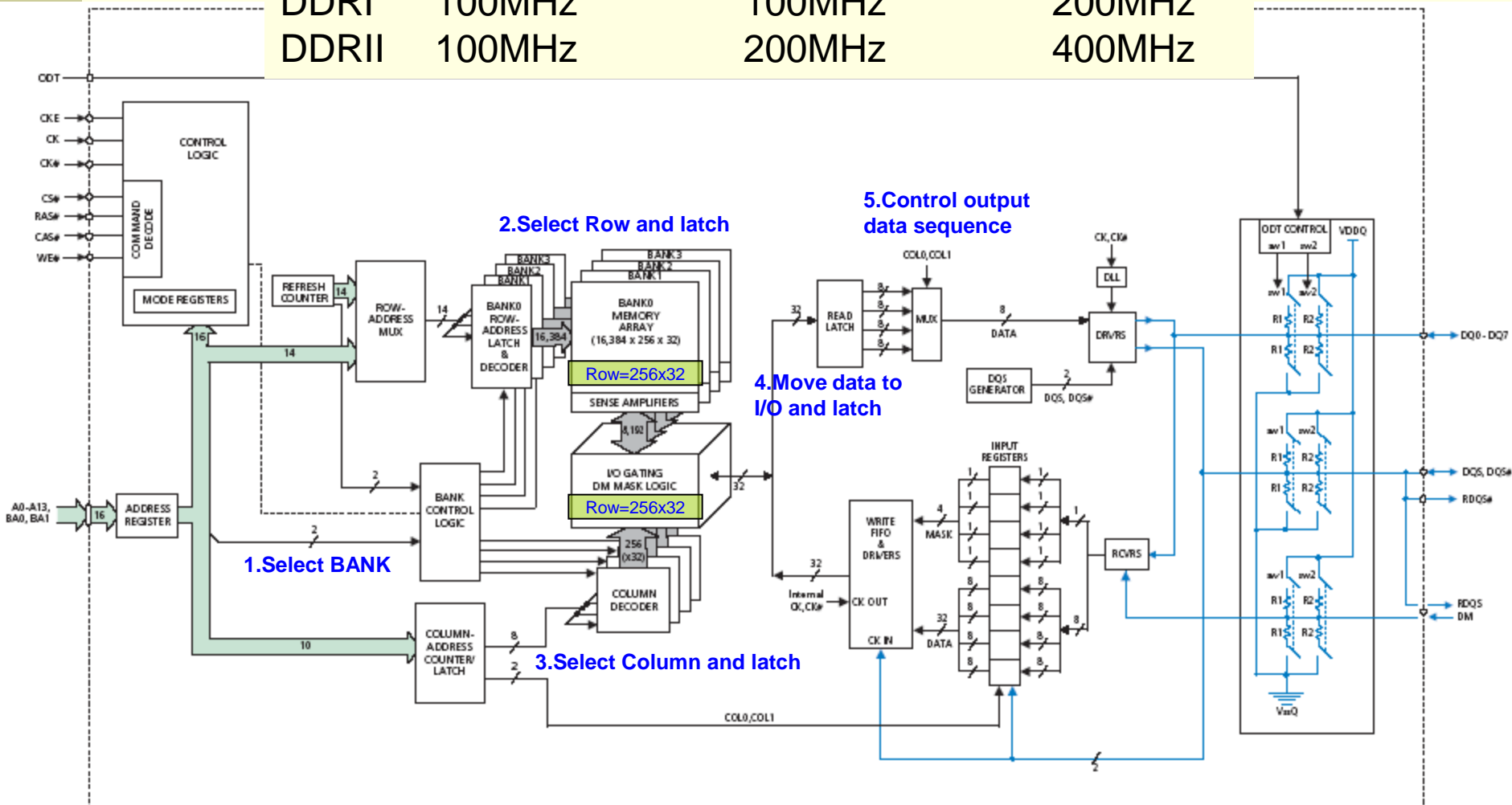
Act: Bank activate command
 Read: Read Command
 P-Rd: Posted Read / Posted CAS
 D: data output
 Green, Blue and Purple:
 represent different bank access

Outline

- DDRI vs. DDRII
- **Functional Block Diagram**
- Simplified State Diagram
- Action of Functional signal Description

Functional Block Diagram (64 Meg x 8)

| | | | | | |
|--------|--------|----------|--------|----------|--------|
| DDR I | 100MHz | External | 100MHz | Data bus | 200MHz |
| DDR II | 100MHz | | 200MHz | | 400MHz |



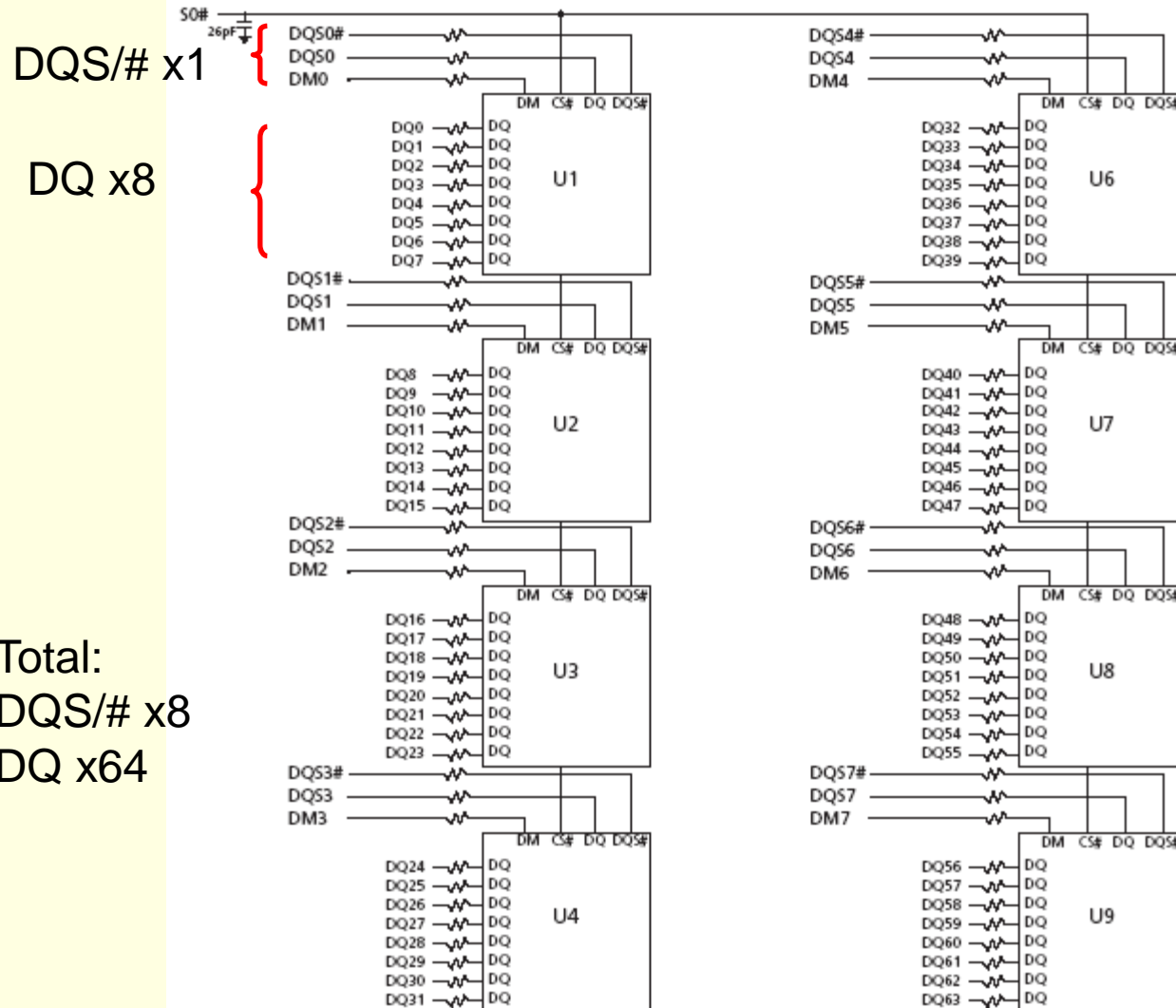
Pin Descriptions

| Symbol | Type | Function |
|--|-------|--|
| CK, $\overline{\text{CK}}$ | Input | Clock: CK and $\overline{\text{CK}}$ are differential clock inputs. All address and control input signals are sampled on the crossing of the positive edge of CK and negative edge of $\overline{\text{CK}}$. Output (read) data is referenced to the crossings of CK and $\overline{\text{CK}}$ (both directions of crossing). |
| CKE | Input | Clock Enable: CKE HIGH activates, and CKE Low deactivates, internal clock signals and device input buffers and output drivers. Taking CKE Low provides Precharge Power-Down and Self Refresh operation (all banks idle), or Active Power-Down (row Active in any bank). CKE is synchronous for power down entry and exit, and for self refresh entry. CKE is asynchronous for self refresh exit. After VREF has become stable during the power on and initialization sequence, it must be maintained for proper operation of the CKE receiver. For proper self-refresh entry and exit, VREF must be maintained to this input. CKE must be maintained high throughout read and write accesses. Input buffers, excluding CK, $\overline{\text{CK}}$, ODT and CKE are disabled during power-down. Input buffers, excluding CKE, are disabled during self refresh. |
| $\overline{\text{CS}}$ | Input | Chip Select: All commands are masked when $\overline{\text{CS}}$ is registered HIGH. $\overline{\text{CS}}$ provides for external Rank selection on systems with multiple Ranks. $\overline{\text{CS}}$ is considered part of the command code. |
| ODT | Input | On Die Termination: ODT (registered HIGH) enables termination resistance internal to the DDR2 SDRAM. When enabled, ODT is only applied to each DQ, DQS, $\overline{\text{DQS}}$, RDQS, $\overline{\text{RDQS}}$, and DM signal for x4/x8 configurations. For x16 configuration ODT is applied to each DQ, UDQS/ $\overline{\text{UDQS}}$, LDQS/ $\overline{\text{LDQS}}$, UDM, and LDM signal. The ODT pin will be ignored if the Extended Mode Register (EMRS(1)) is programmed to disable ODT. |
| $\overline{\text{RAS}}$, $\overline{\text{CAS}}$, $\overline{\text{WE}}$ | Input | Command Inputs: $\overline{\text{RAS}}$, $\overline{\text{CAS}}$ and $\overline{\text{WE}}$ (along with $\overline{\text{CS}}$) define the command being entered. |
| DM (UDM), (LDM) | Input | Input Data Mask: DM is an input mask signal for write data. Input data is masked when DM is sampled HIGH coincident with that input data during a Write access. DM is sampled on both edges of DQS. Although DM pins are input only, the DM loading matches the DQ and DQS loading. For x8 device, the function of DM or RDQS/ $\overline{\text{RDQS}}$ is enabled by EMRS command. |

Pin Descriptions

| | | |
|--|--------------|---|
| BA0 - BA2 | Input | Bank Address Inputs: BA0 - BA2 define to which bank an Active, Read, Write or Precharge command is being applied (For 256Mb and 512Mb, BA2 is not applied). Bank address also determines if the mode register or extended mode register is to be accessed during a MRS or EMRS cycle. |
| A0 - A15 | Input | Address Inputs: Provided the row address for Active commands and the column address and Auto Precharge bit for Read/Write commands to select one location out of the memory array in the respective bank. A10 is sampled during a Precharge command to determine whether the Precharge applies to one bank (A10 LOW) or all banks (A10 HIGH). If only one bank is to be precharged, the bank is selected by BA0 - BA2. The address inputs also provide the op-code during Mode Register Set commands. |
| DQ | Input/Output | Data Input/ Output: Bi-directional data bus. |
| DQS, $\overline{\text{DQS}}$ (UDQS), $\overline{\text{UDQS}}$ (LDQS), $\overline{\text{LDQS}}$ (RDQS), $\overline{\text{RDQS}}$ | Input/Output | <p>Data Strobe: output with read data, input with write data. Edge-aligned with read data, centered in write data. For the x16, LDQS corresponds to the data on DQ0-DQ7; UDQS corresponds to the data on DQ8-DQ15. For the x8, an RDQS option using DM pin can be enabled via the EMRS(1) to simplify read timing. The data strobes DQS, LDQS, UDQS, and RDQS may be used in single ended mode or paired with optional complementary signals $\overline{\text{DQS}}$, $\overline{\text{LDQS}}$, $\overline{\text{UDQS}}$, and $\overline{\text{RDQS}}$ to provide differential pair signaling to the system during both reads and writes. An EMRS(1) control bit enables or disables all complementary data strobe signals.</p> <p>In this data sheet, "differential DQS signals" refers to any of the following with A10 = 0 of EMRS(1)</p> <ul style="list-style-type: none"> x4 DQS/$\overline{\text{DQS}}$ x8 DQS/$\overline{\text{DQS}}$ if EMRS(1)[A11] = 0 x8 DQS/$\overline{\text{DQS}}$, RDQS/$\overline{\text{RDQS}}$, if EMRS(1)[A11] = 1 x16 LDQS/$\overline{\text{LDQS}}$ and UDQS/$\overline{\text{UDQS}}$ <p>"single-ended DQS signals" refers to any of the following with A10 = 1 of EMRS(1)</p> <ul style="list-style-type: none"> x4 DQS x8 DQS if EMRS(1)[A11] = 0 x8 DQS, RDQS, if EMRS(1)[A11] = 1 x16 LDQS and UDQS |
| NC | | No Connect: No internal electrical connection is present. |
| V _{DDQ} | Supply | DQ Power Supply: 1.8V +/- 0.1V |
| V _{SSQ} | Supply | DQ Ground |
| V _{DDL} | Supply | DLL Power Supply: 1.8V +/- 0.1V |
| V _{SSDL} | Supply | DLL Ground |

SDRAM Slot (x8)



Pin Descriptions

Address are for all chips

18/3

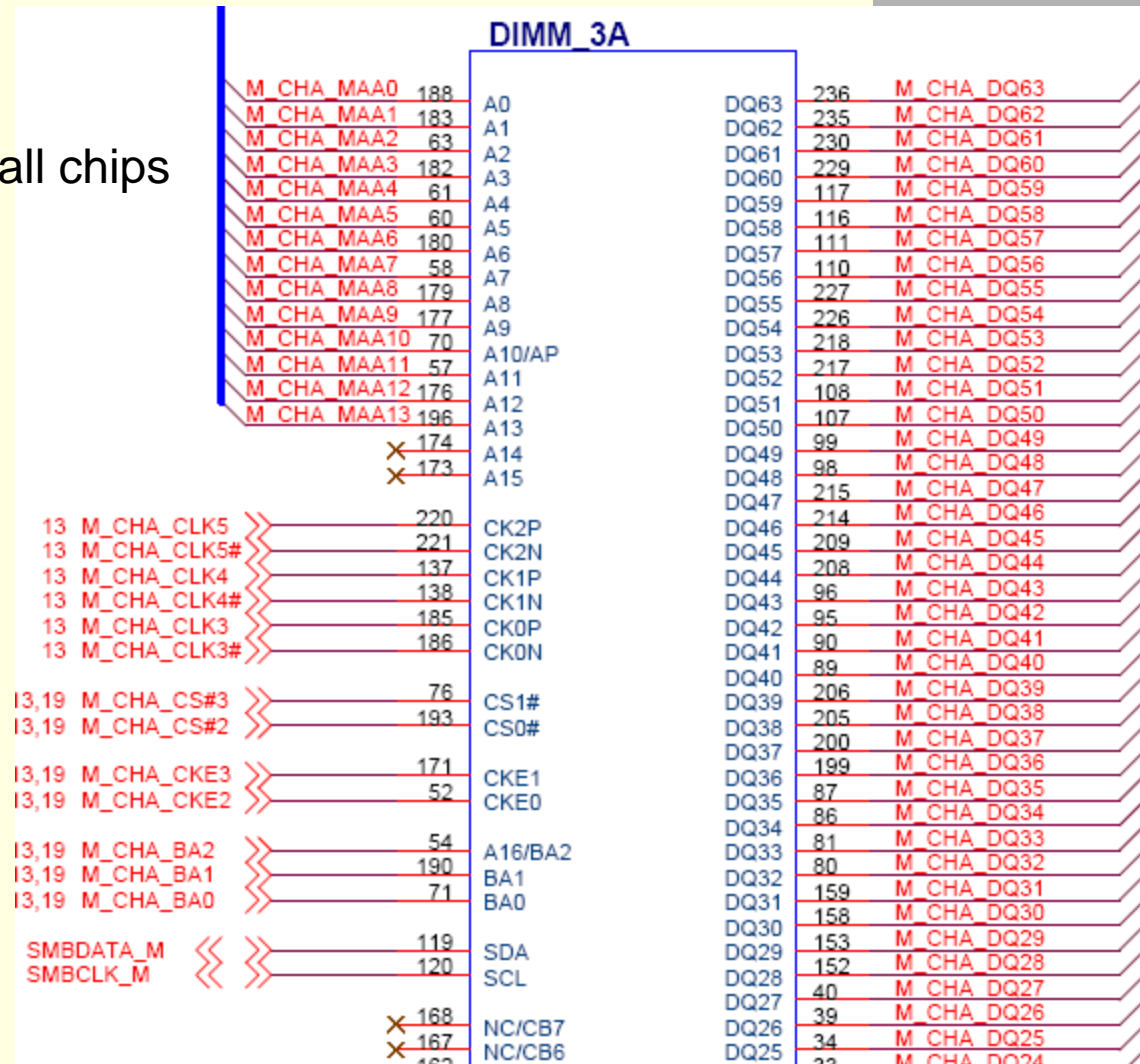
Chip select:
for Rank selection

X8,4bank need 2pin
X16,8bank need 3pin

SMBus

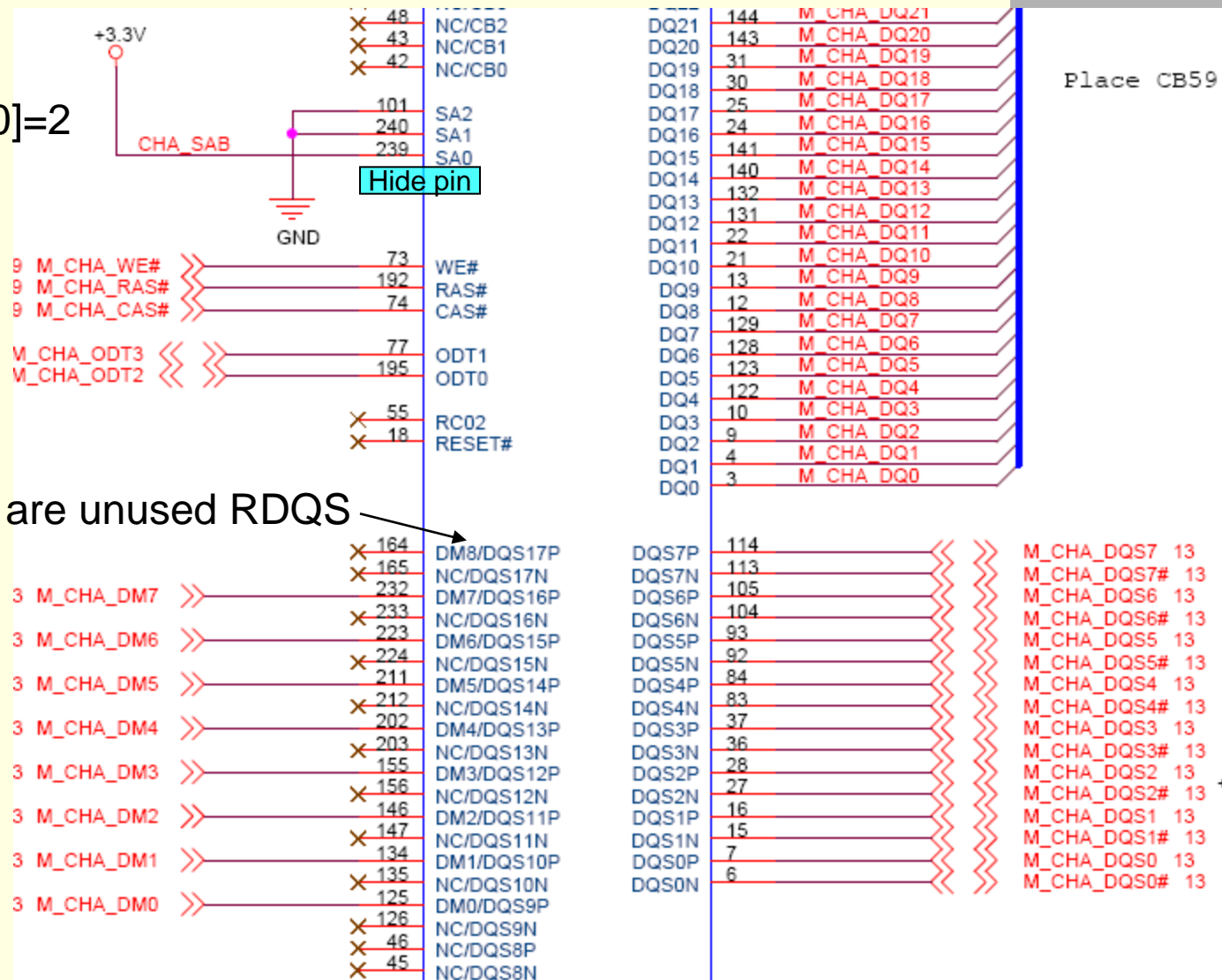
7~1

0

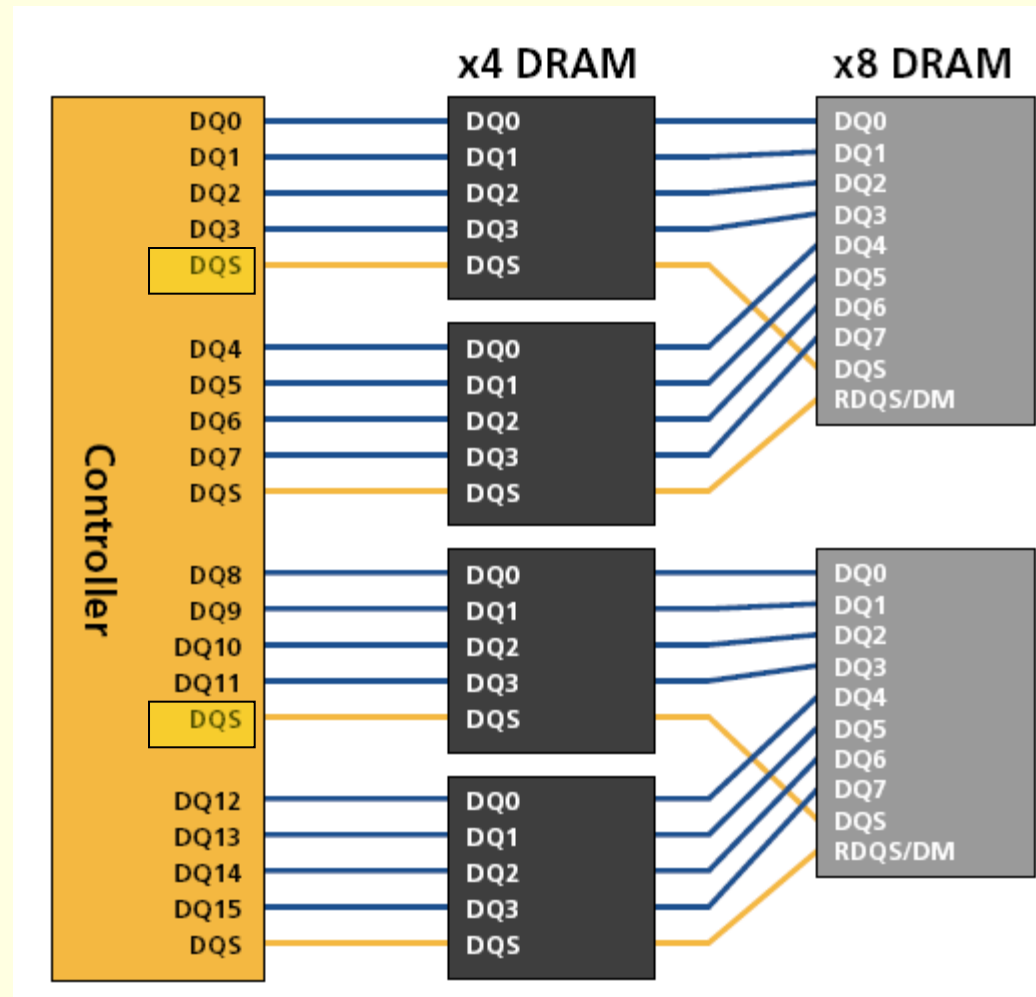


Pin Descriptions

Read
[0 0 1 0]=2
Write
2+1=3



RDQS: Redundant DQS

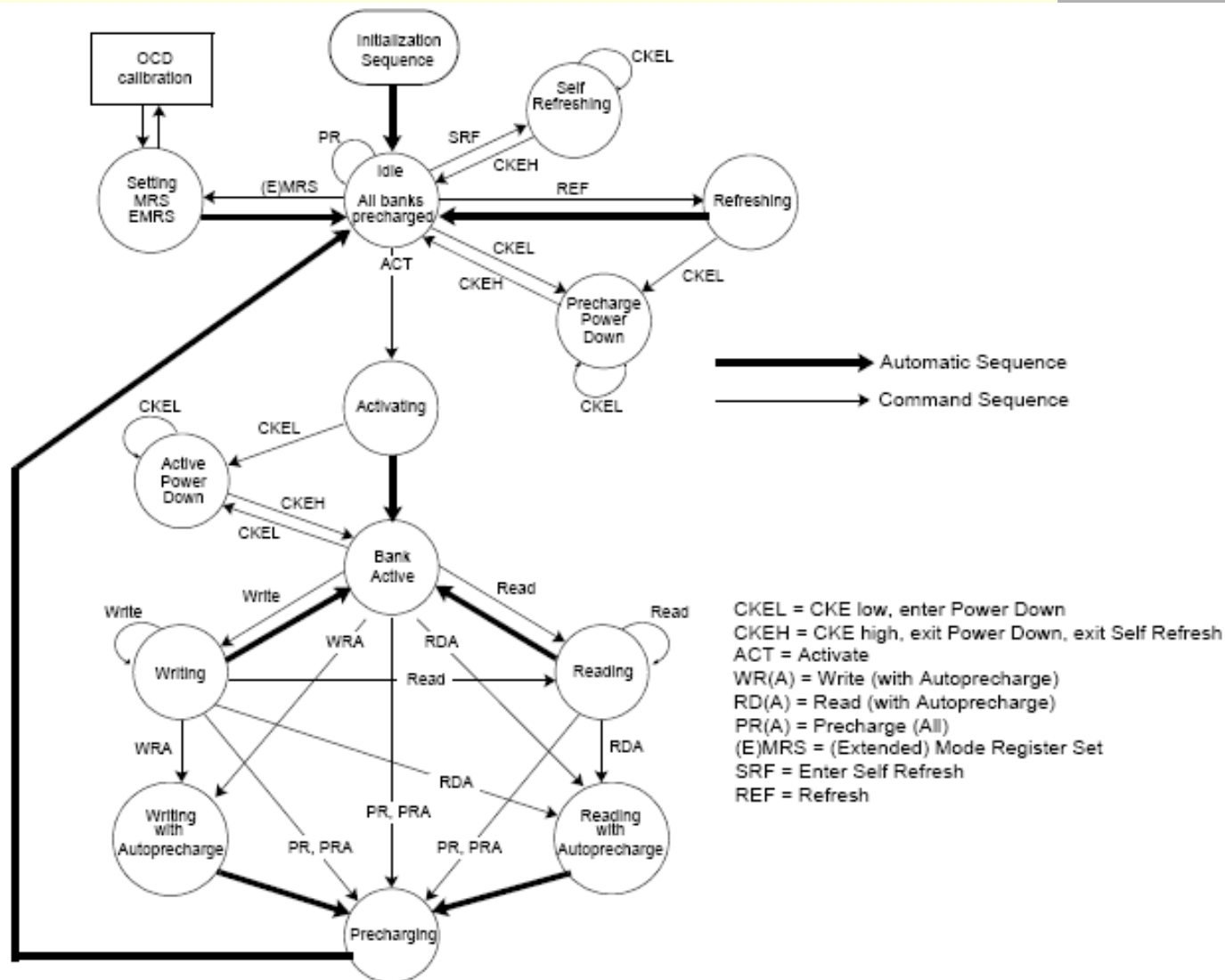


*Controller must support X4 DRAM

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- **Simplified State Diagram**
- Action of Functional signal Description

Simplified State Diagram

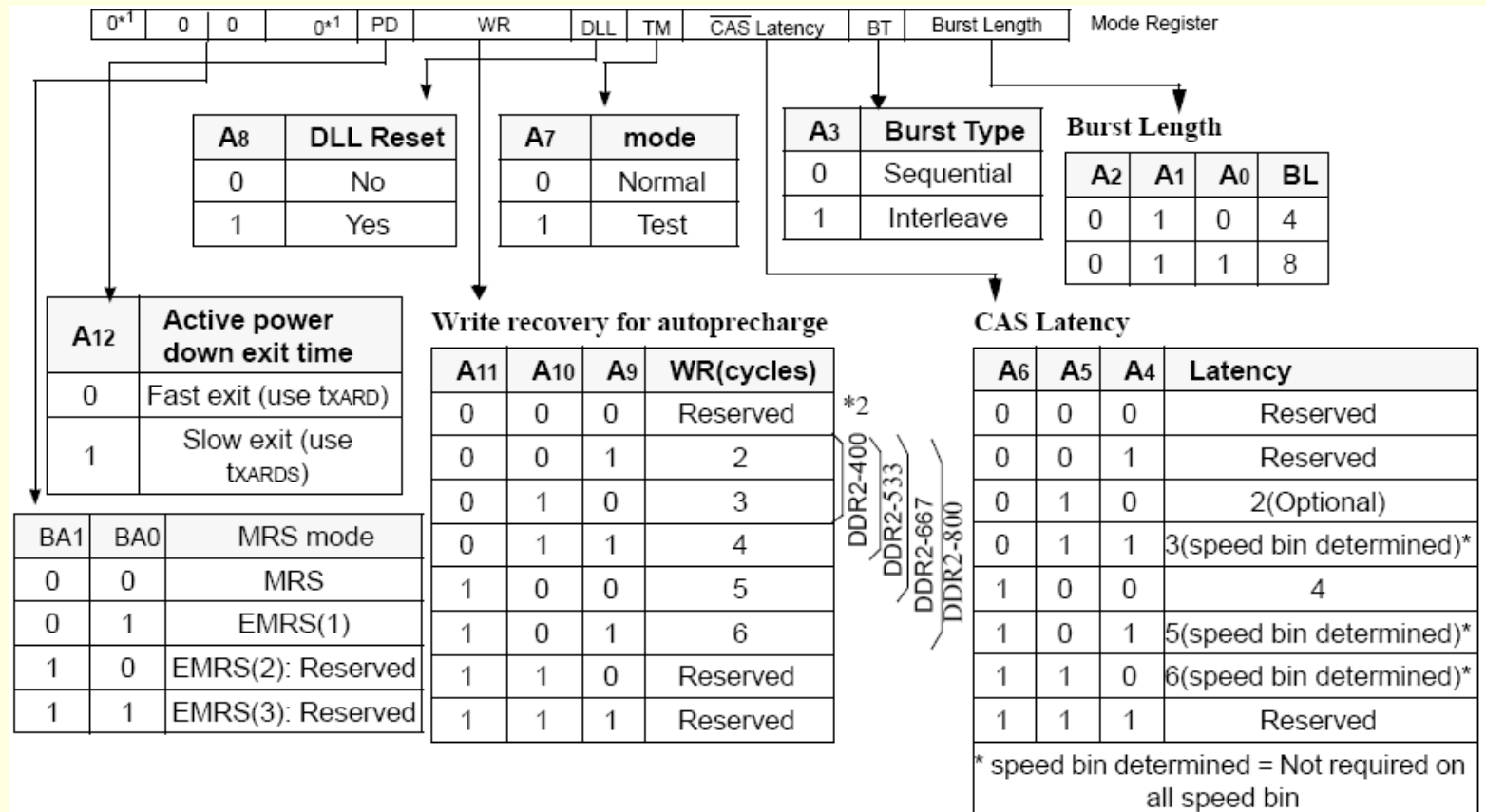


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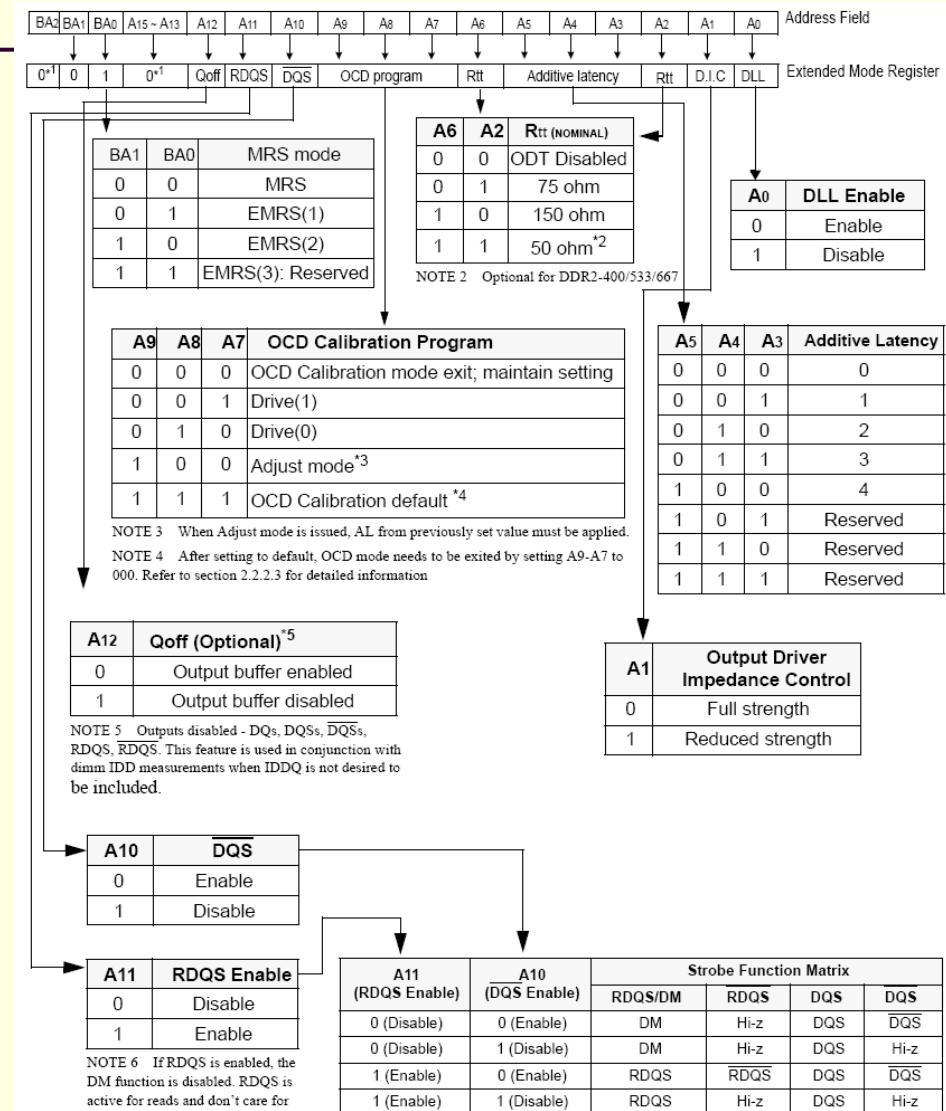
Mode Register Set (MRS)

- Control CAS latency, burst length, burst sequence, test mode, DLL reset, tWR



Extended Mode Register Set (EMRS)

- Stores the data for enabling or disabling the DLL, output driver strength, additive latency, ODT, DQS disable, OCD program, RDQS enable.



Bank Active Command

- The bank addresses BA0 ~ BA2 are used to select the desired bank.
- The row address A0 through A15 is used to determine which row to activate in the selected bank.
- Once a bank has been activated it must be precharged.

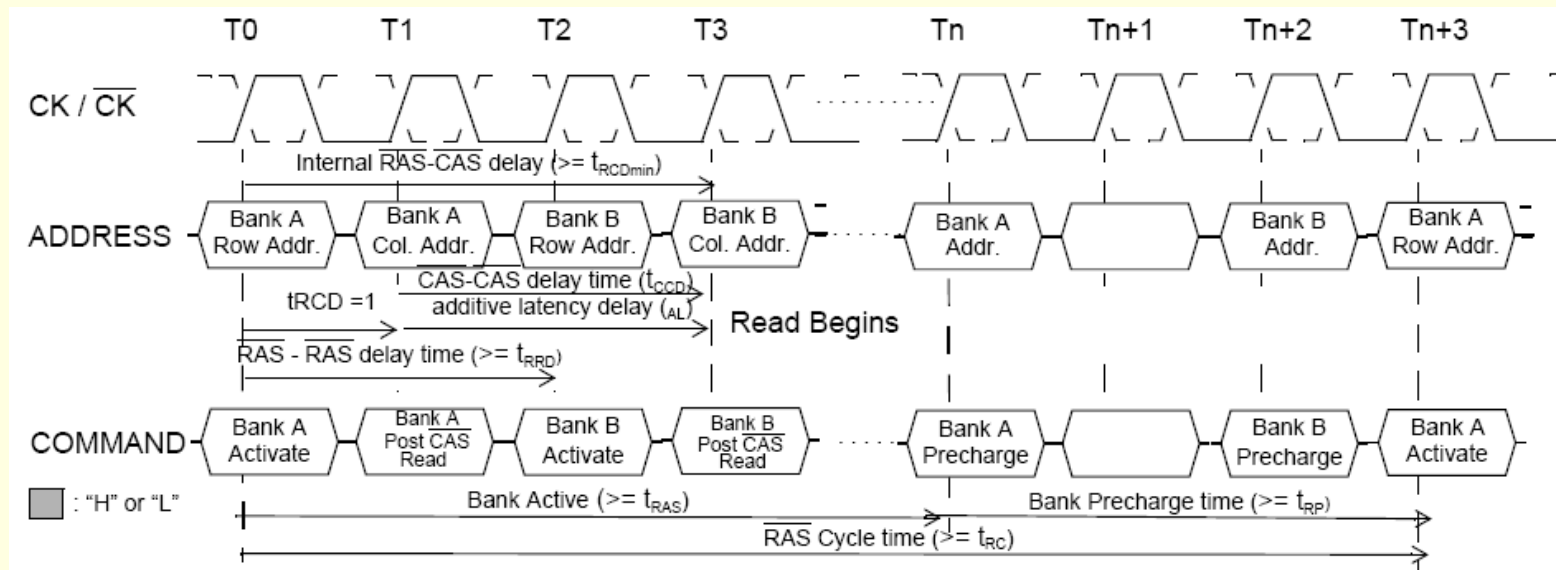
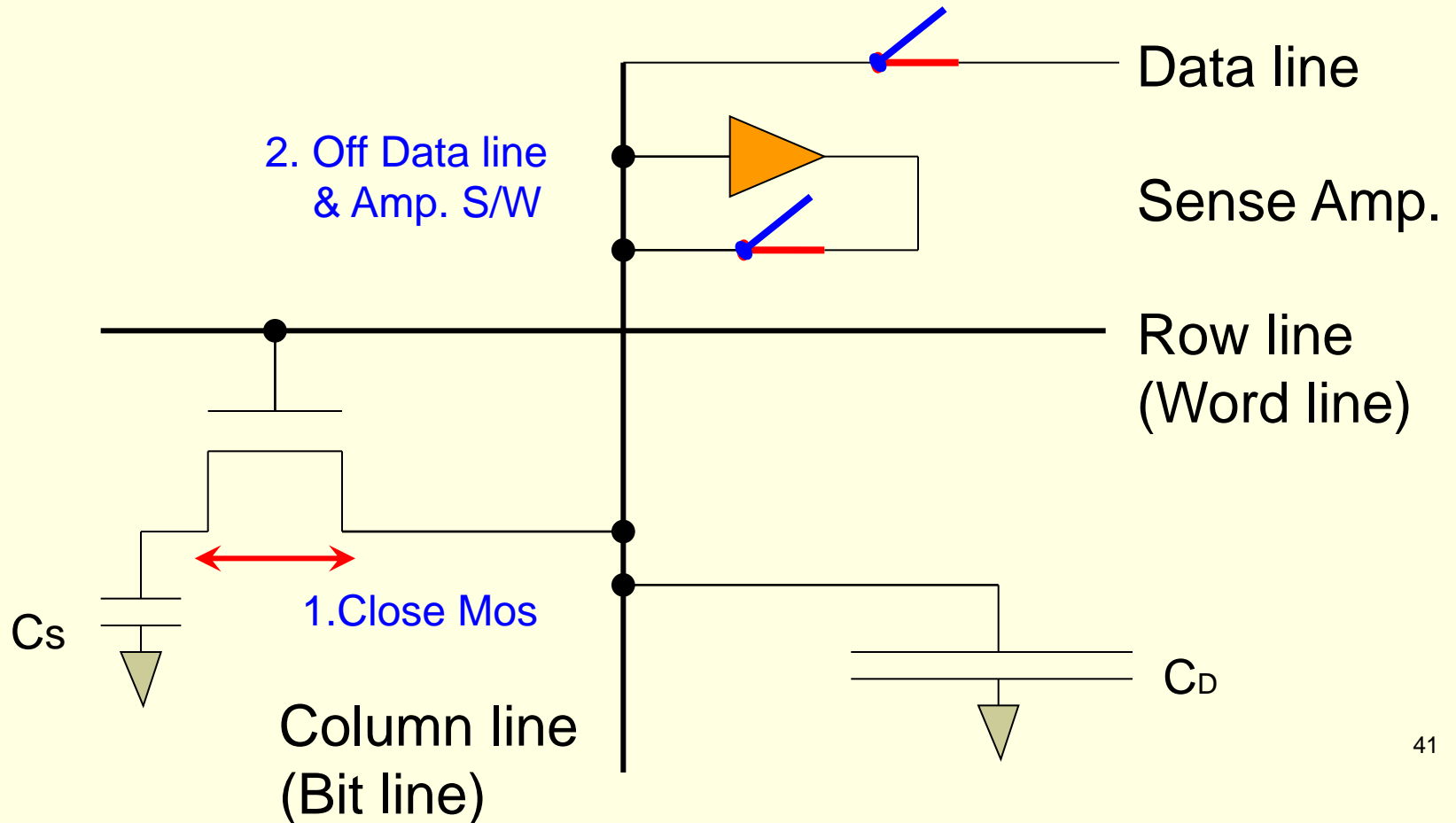


Figure 20 — Bank activate command cycle: $t_{RCD} = 3$, $AL = 2$, $t_{RP} = 3$, $t_{RRD} = 2$, $t_{CCD} = 2$

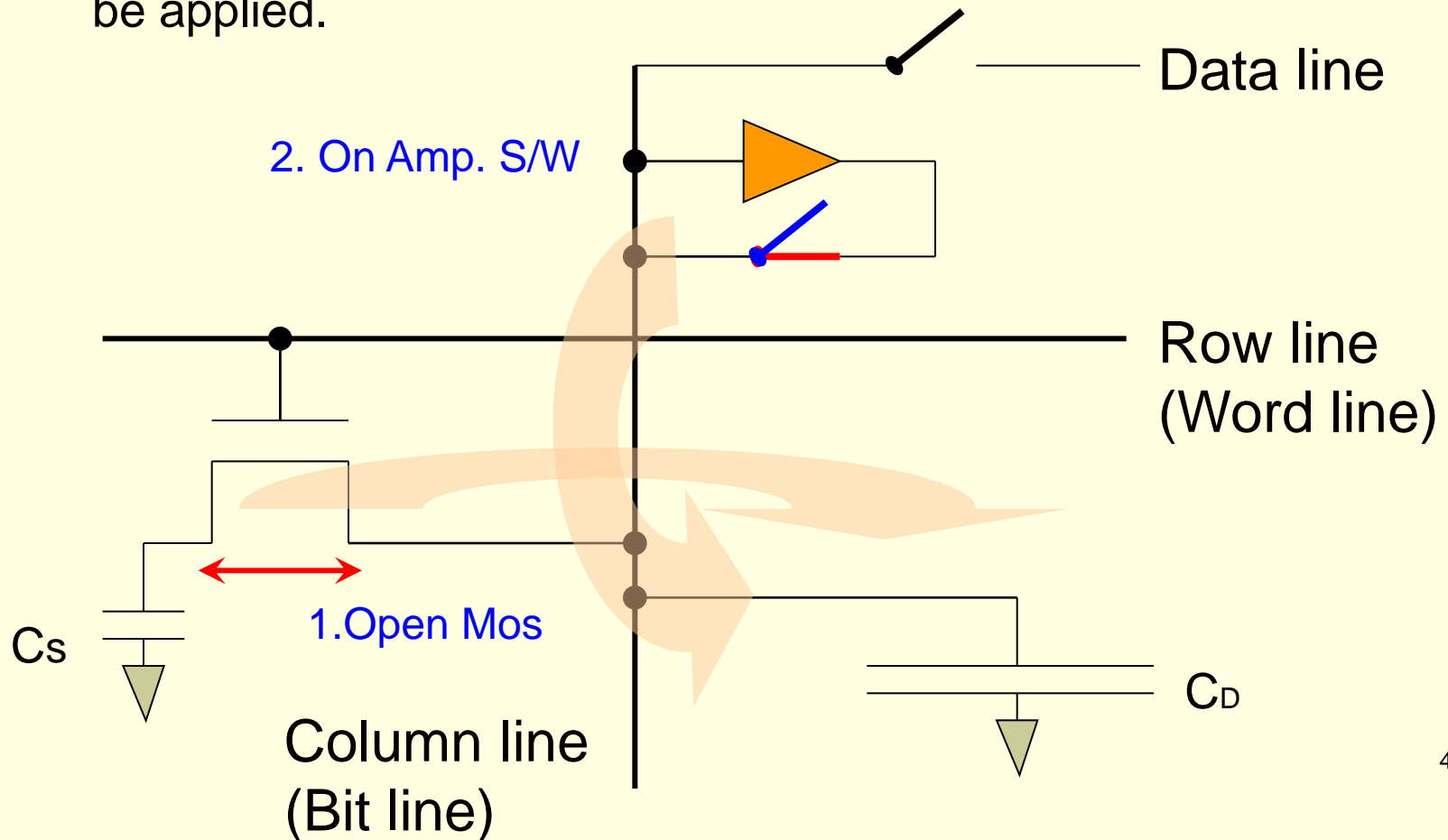
Precharge

- Precharge Command is used to precharge or close a bank that has been activated.



Refresh

- All banks must be precharged and idle for a minimum of the Precharge time (t_{RP}) before the Refresh command (REF) can be applied.



Refresh Command

- All banks must be precharged and idle for a minimum of the Precharge time (t_{RP}) before the Refresh command (REF) can be applied.

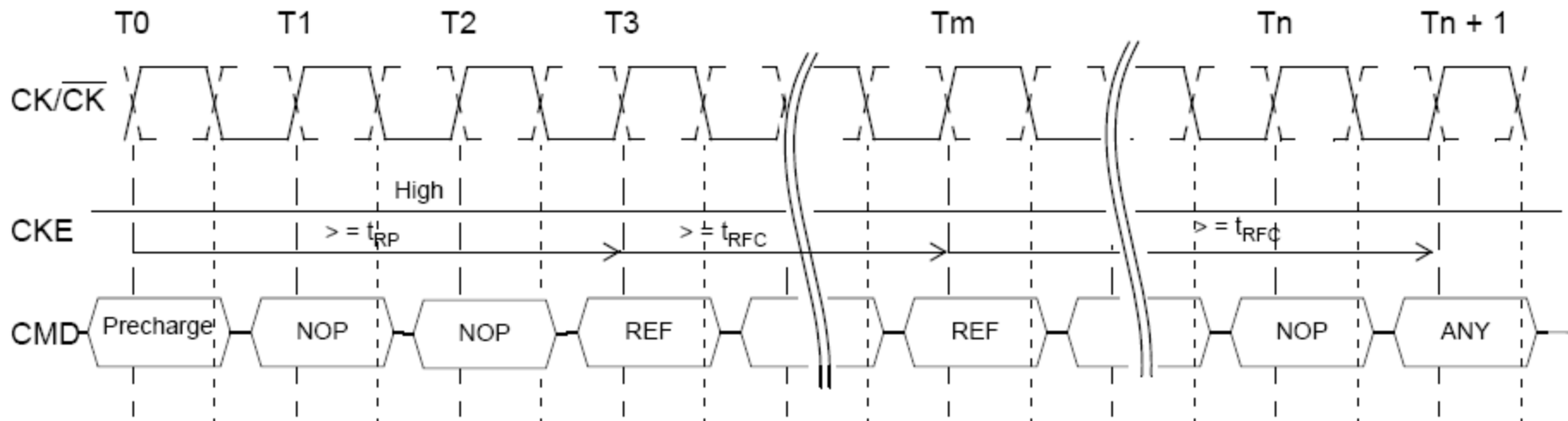
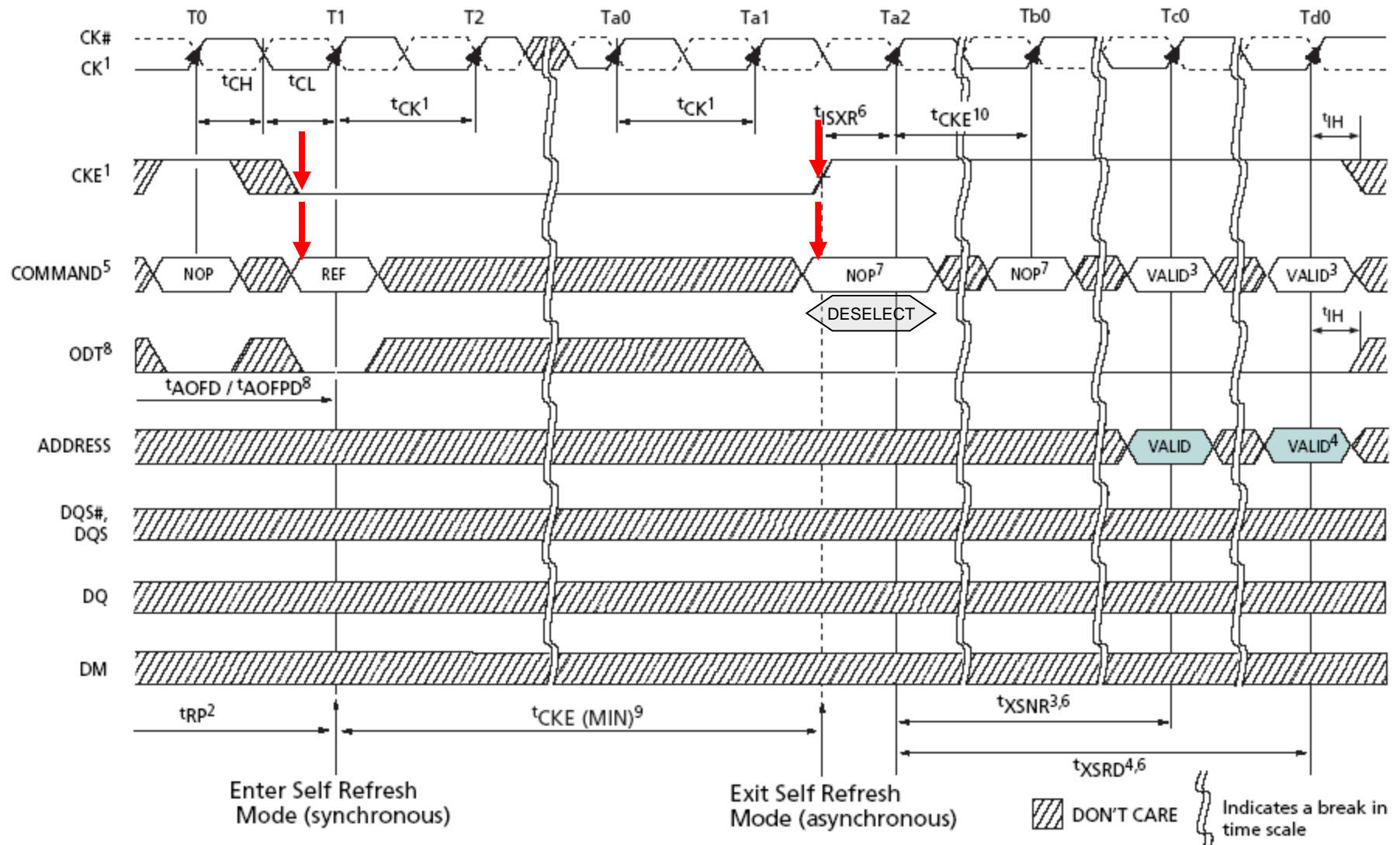


Figure 49 — Refresh command

Self Refresh Operation



Burst Read Command

- $RL = AL + CL$
- When $AL = 2$

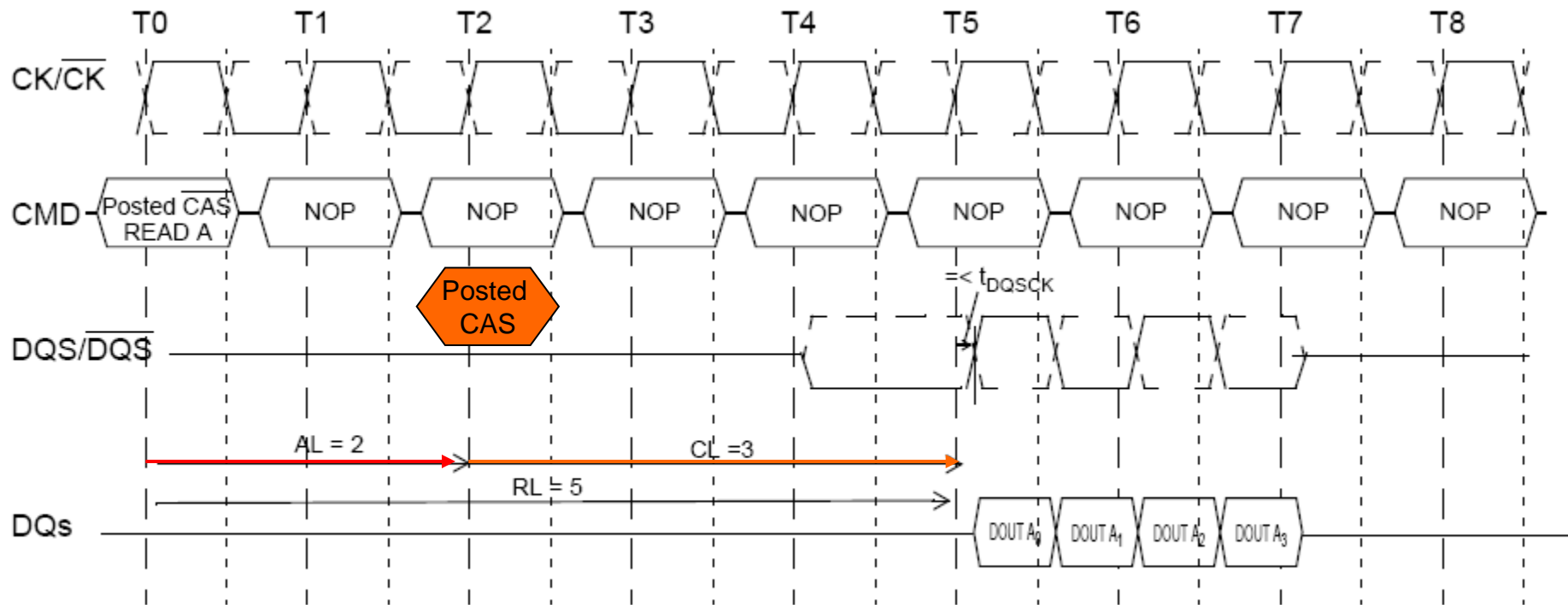


Figure 24 — Burst read operation: $RL = 5$ ($AL = 2$, $CL = 3$, $BL = 4$)

Burst Read Command

■ When AL=0

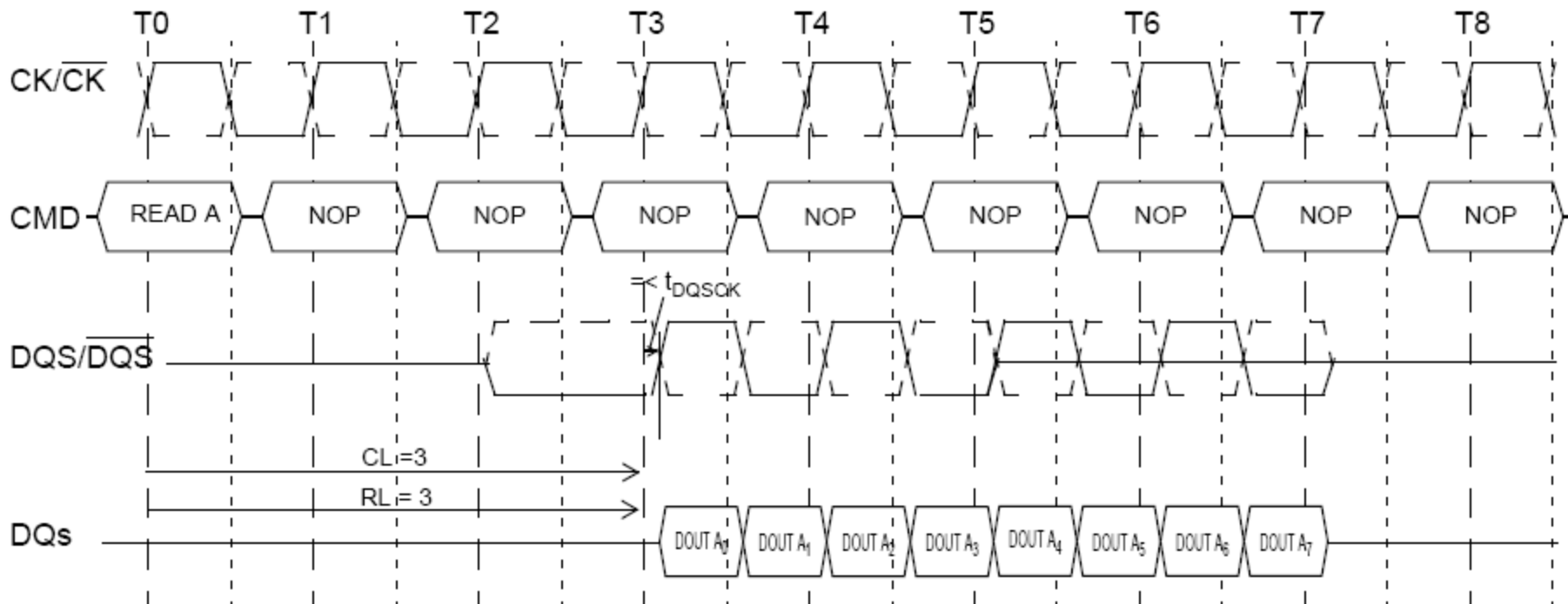


Figure 25 — Burst read operation: $RL = 3$ ($AL = 0$ and $CL = 3$, $BL = 8$)

Burst Write Command

■ $WL=RL-1$

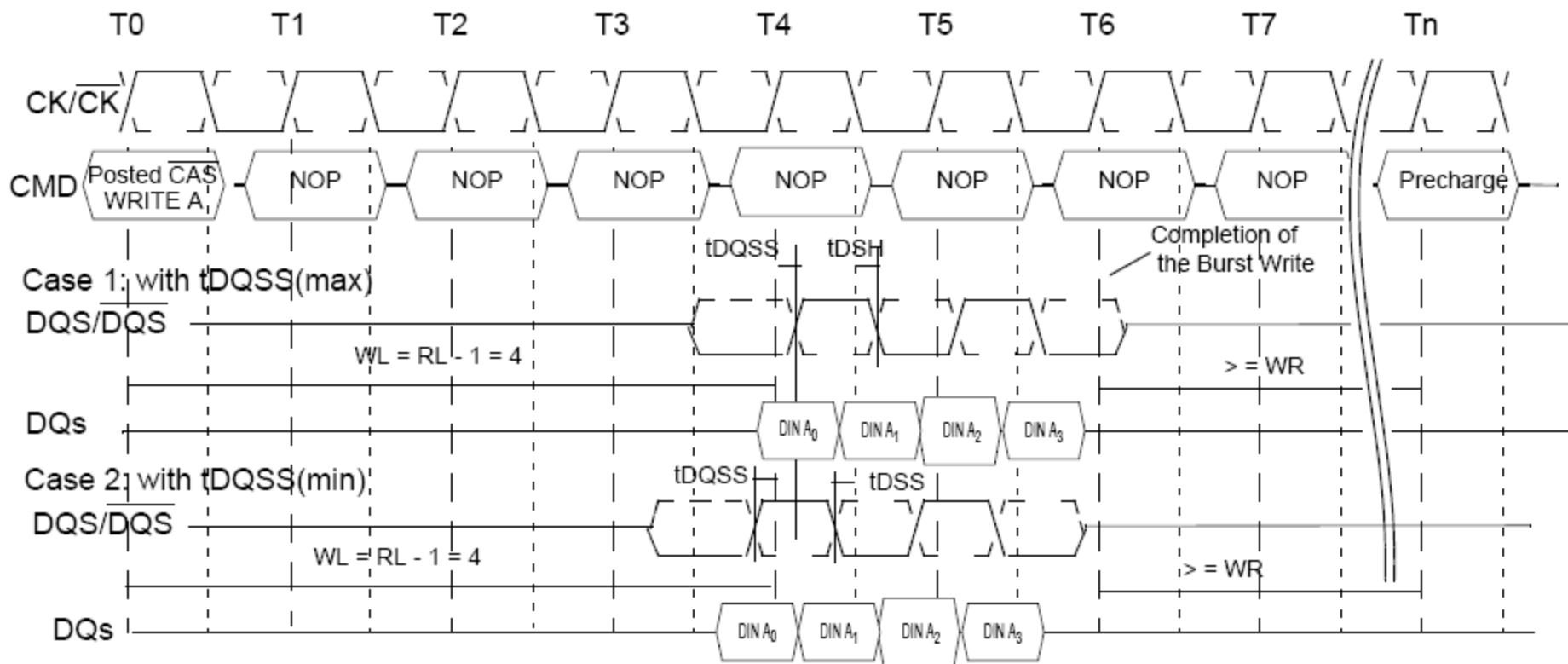


Figure 30 — Burst write operation: $RL = 5$ ($AL=2$, $CL=3$), $WL = 4$, $WR = 3$, $BL = 4$

* t_{DQSS} : First DQS latching transition to associated clock edge

Burst Read followed by Burst Write

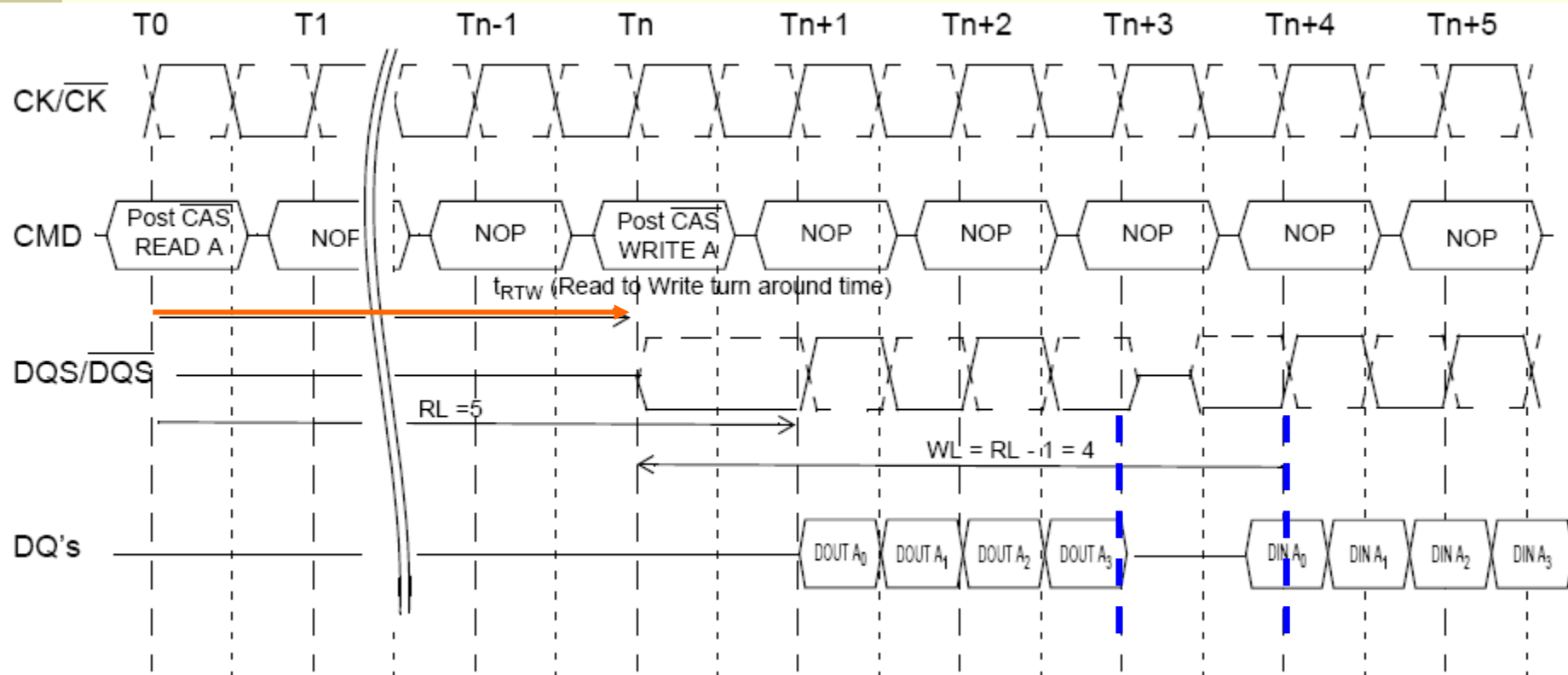
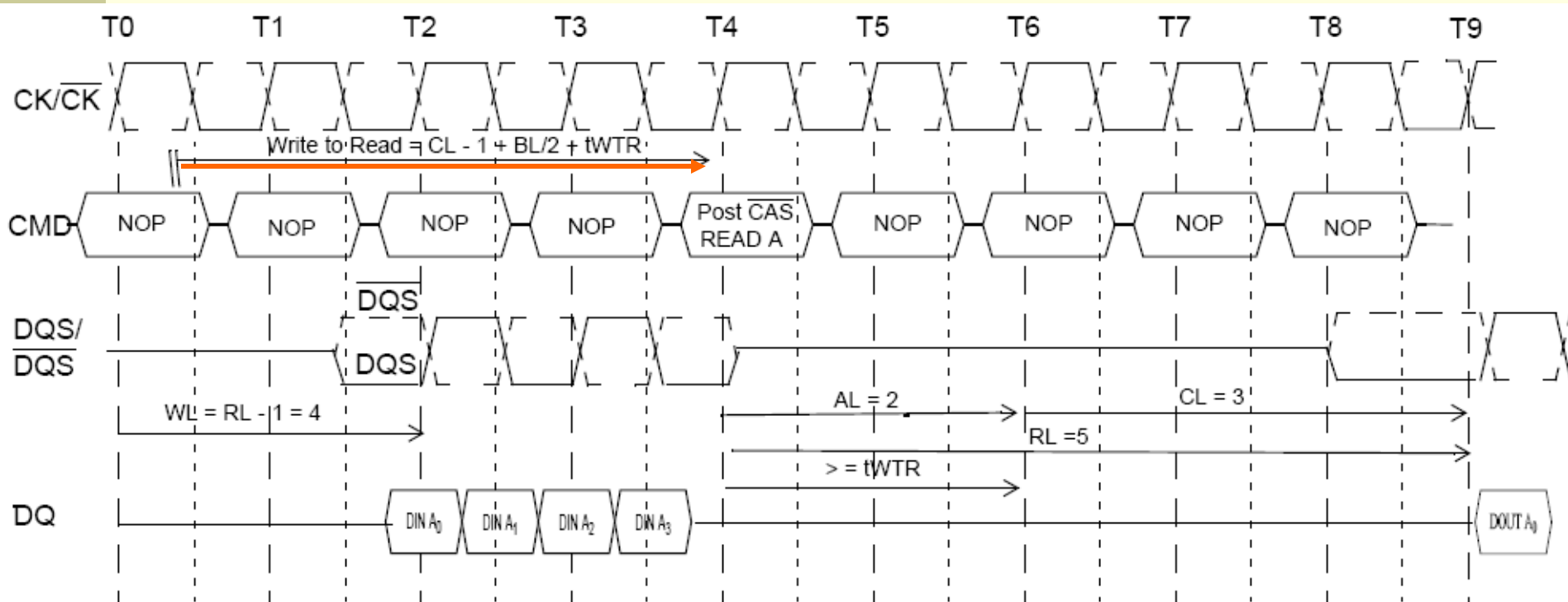


Figure 26 — Burst read followed by burst write: $RL = 5$, $WL = (RL-1) = 4$, $BL = 4$

* t_{RTW} : Read to Write turn around time

Burst Write followed by Burst Read



NOTE The minimum number of clock from the burst write command to the burst read command is $[CL - 1 + BL/2 + tWTR]$. This $tWTR$ is not a write recovery time (tWR) but the time required to transfer the 4bit write data from the input buffer into sense amplifiers in the array. $tWTR$ is defined in AC spec table of this data sheet.

Figure 32 — Burst write followed by burst read: $RL = 5$ ($AL=2$, $CL=3$), $WL = 4$, $tWTR = 2$, $BL = 4$

Burst Read operation followed by Precharge

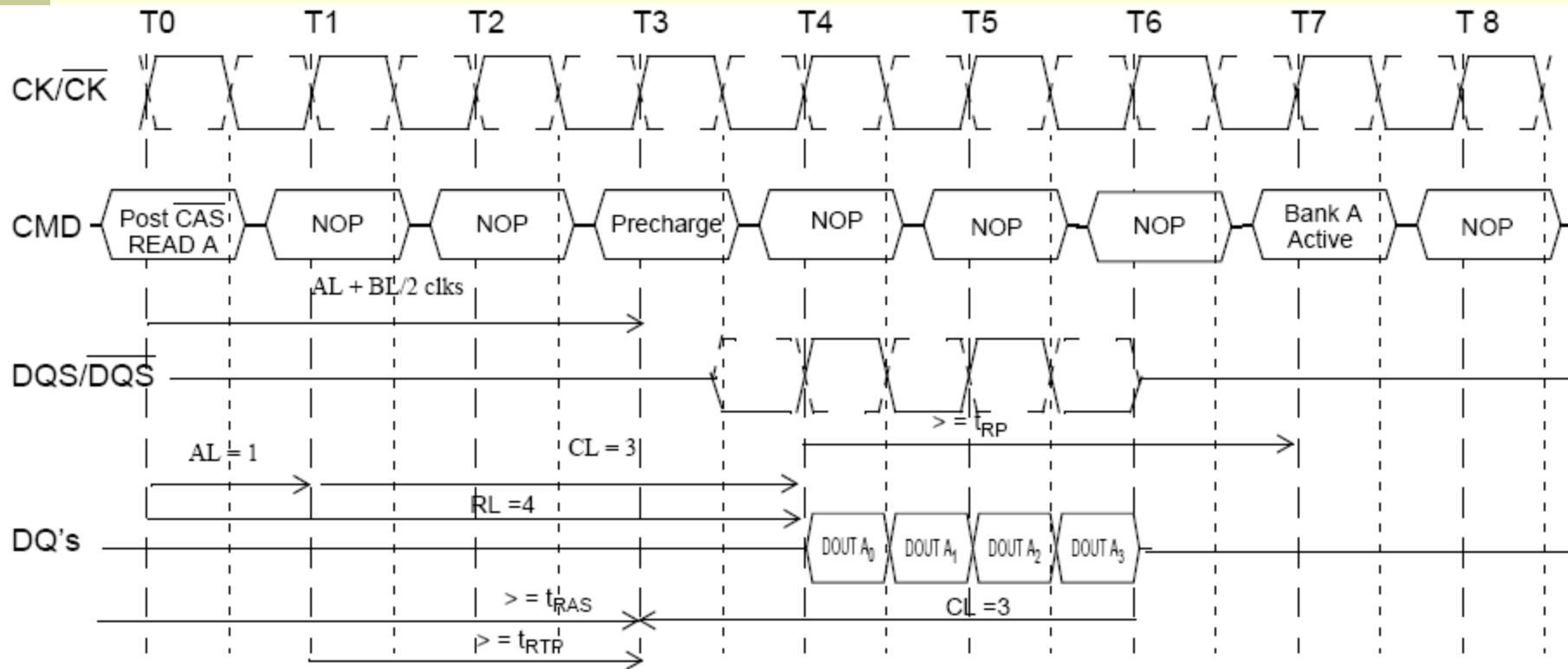


Figure 36 — Example 1: Burst read operation followed by precharge:
 $RL = 4$, $AL = 1$, $CL = 3$, $BL = 4$, $t_{RTP} \leq 2 \text{ clocks}$

Burst Write operation followed by Precharge

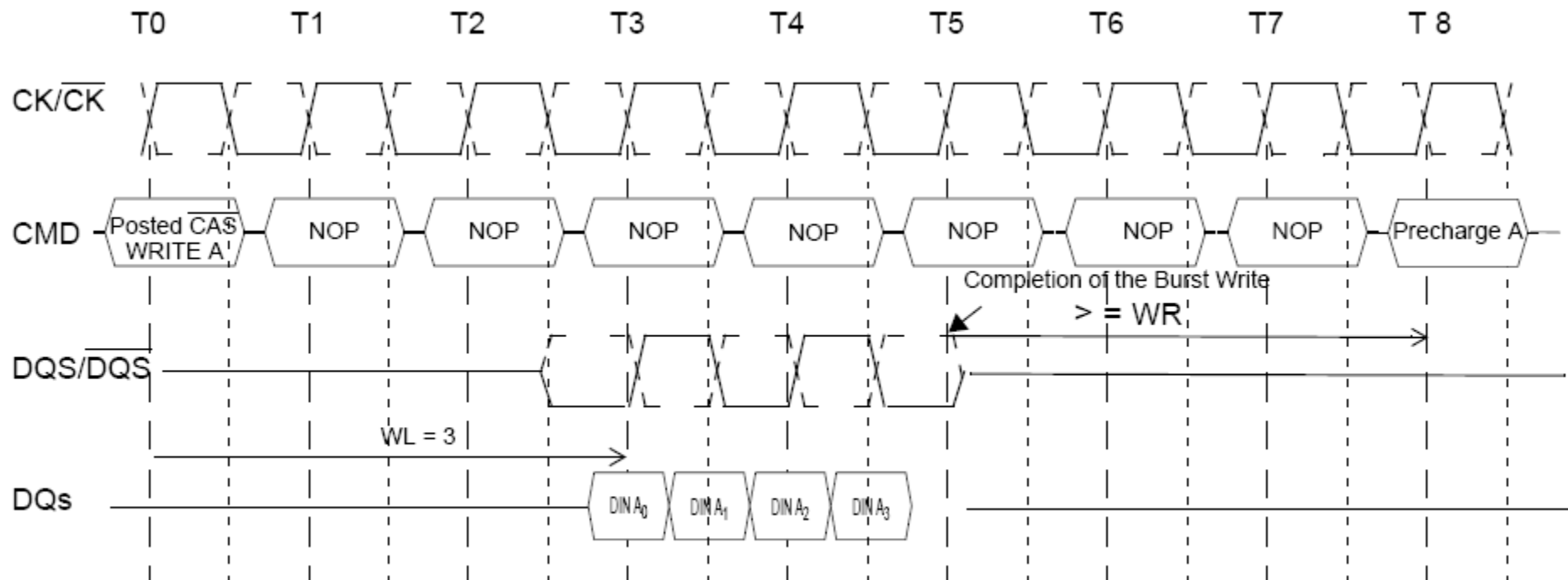


Figure 41 — Example 1: Burst write followed by precharge: $WL = (RL-1) = 3$

Burst Read operation with Auto Precharge

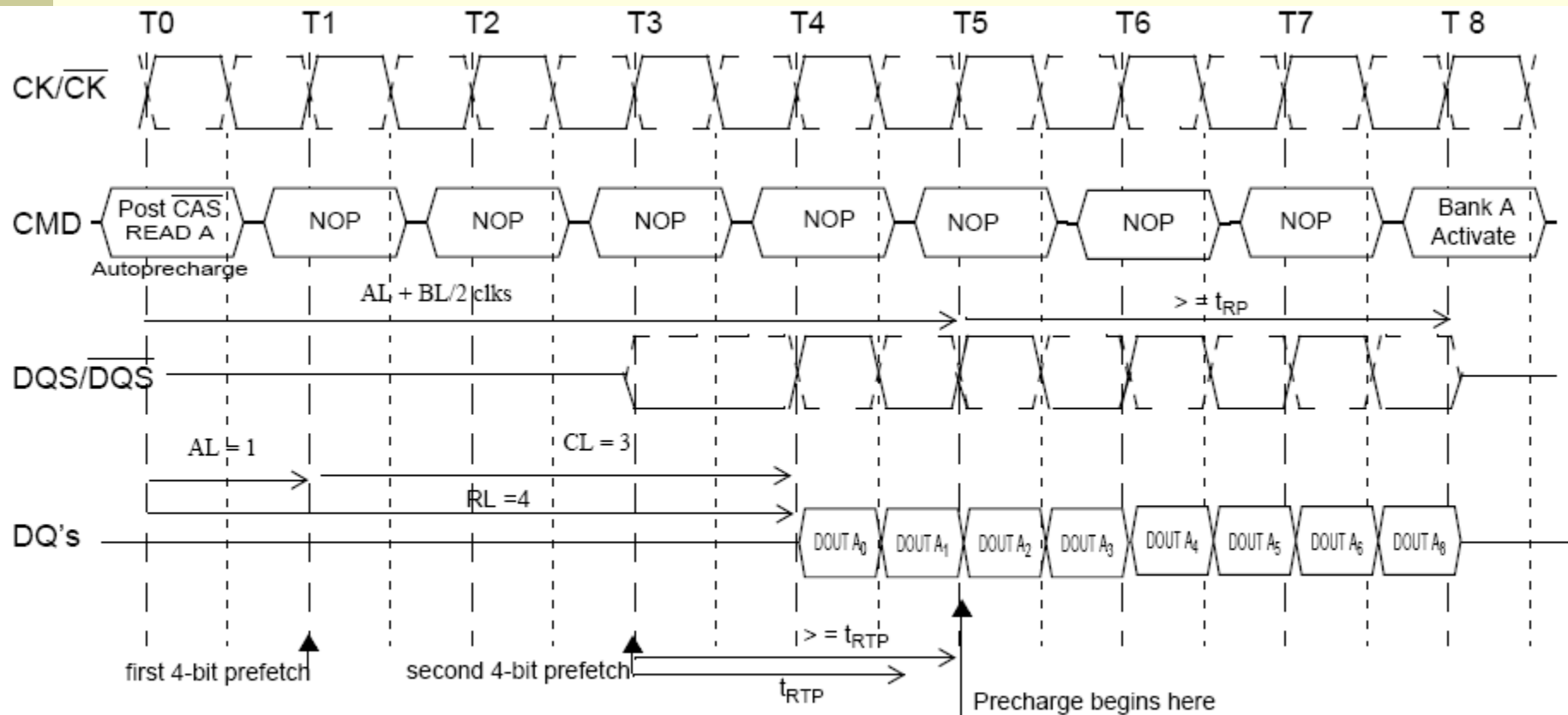


Figure 43 — Example 1: Burst read operation with auto precharge:
 RL = 4, AL = 1, CL = 3, BL = 8, $t_{RTP} \leq 2$ clocks

Burst Write with Auto Precharge

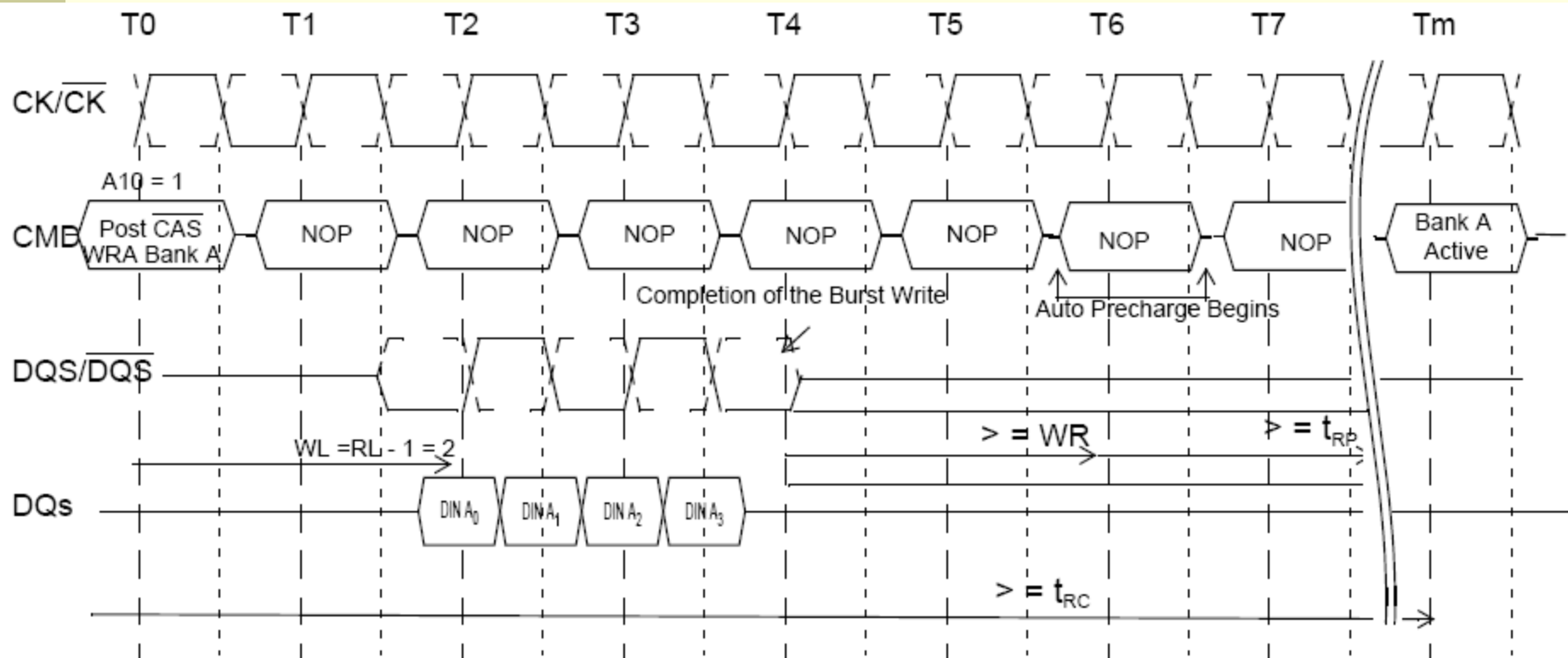
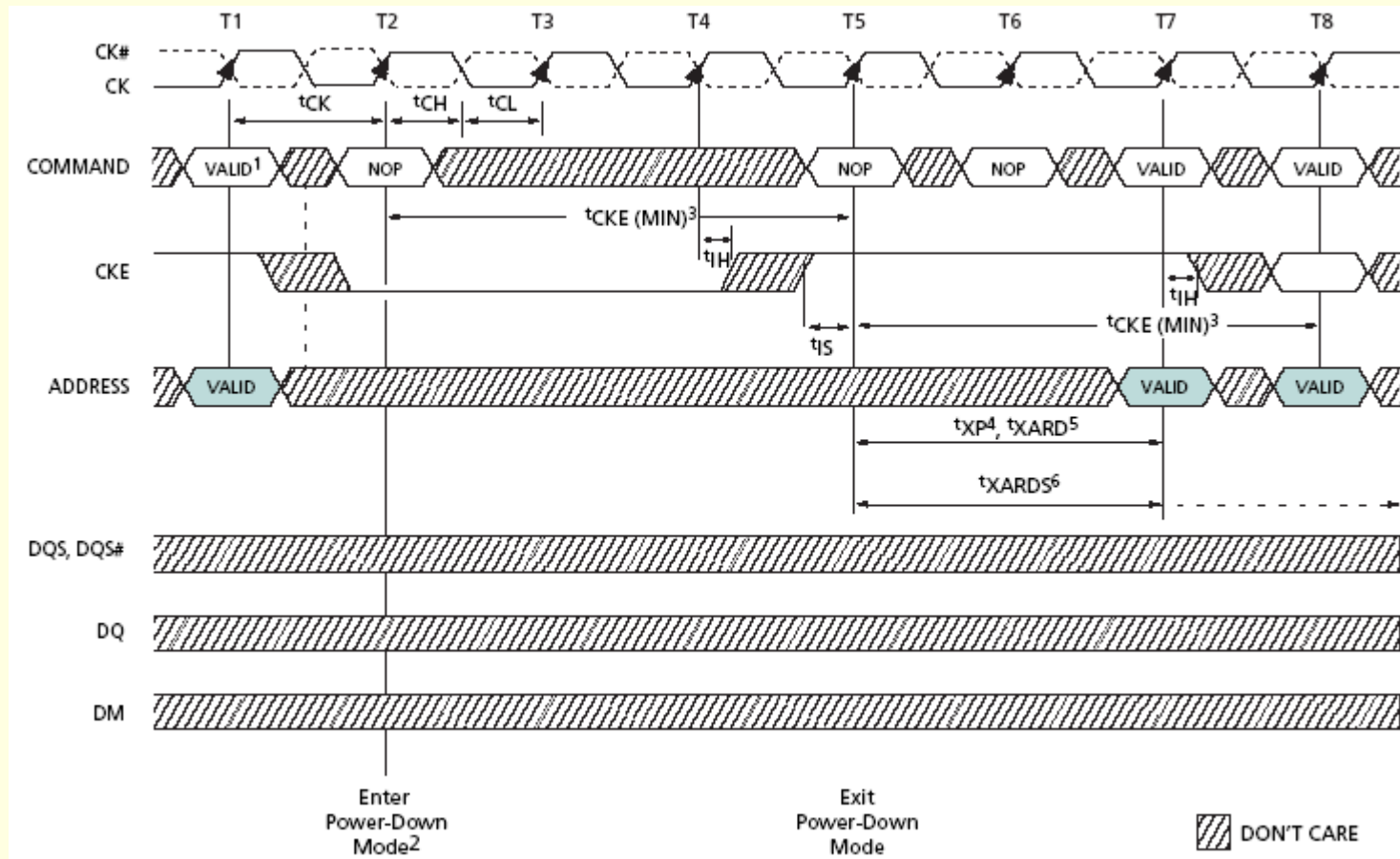


Figure 47 — Burst write with auto-precharge (t_{RC} Limit): $WL = 2$, $t_{WR} = 2$, $BL = 4$, $t_{RP} = 3$

Power-Down Mode

- Entering power-down deactivates the input and output buffers, excluding CK, CK#, ODT, CKE and DLL.



Command Truth Tables

| Function | CKE | | CS# | RAS# | CAS# | WE# | BA1 BA0 | A12 A11 | A10 | A9–A0 | Notes |
|------------------------------|-------------------|------------------|-----|------|------|-----|------------|-------------------|-----|-------------------|-------|
| | Previous Cycle | Current Cycle | | | | | | | | | |
| LOAD MODE | H | H | L | L | L | L | BA | OP Code | | | 2 |
| REFRESH | H | H | L | L | L | H | X | X | X | X | |
| SELF REFRESH Entry | H | L | L | L | L | H | X | X | X | X | |
| SELF REFRESH Exit | L | H | H | X | X | X | X | X | X | X | 7 |
| | | | L | H | H | H | | | | | |
| Single Bank Precharge | H | H | L | L | H | L | BA | X | L | X | 2 |
| All Banks PRECHARGE | H | H | L | L | H | L | X | X | H | X | |
| Bank Activate | H | H | L | L | H | H | BA | Row Address | | | |
| WRITE | H | H | L | H | L | L | BA | Column Address | L | Column Address | 2, 3 |
| WRITE with Auto Precharge | H | H | L | H | L | L | BA | Column Address | H | Column Address | 2, 3 |
| READ | H | H | L | H | L | H | BA | Column Address | L | Column Address | 2, 3 |
| READ with Auto Precharge | H | H | L | H | L | H | BA | Column Address | H | Column Address | 2, 3 |
| NO OPERATION | H | X | L | H | H | H | X | X | X | X | |
| Device Deselect | H | X | H | X | X | X | X | X | X | X | |
| POWER-DOWN Entry | H | L | H | X | X | X | X | X | X | X | 4 |
| | | | L | H | H | H | | | | | |
| POWER-DOWN Exit | L | H | H | X | X | X | X | X | X | X | 4 |
| | | | L | H | H | H | | | | | |